

Breaking Barriers to Moore's Law

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Outline

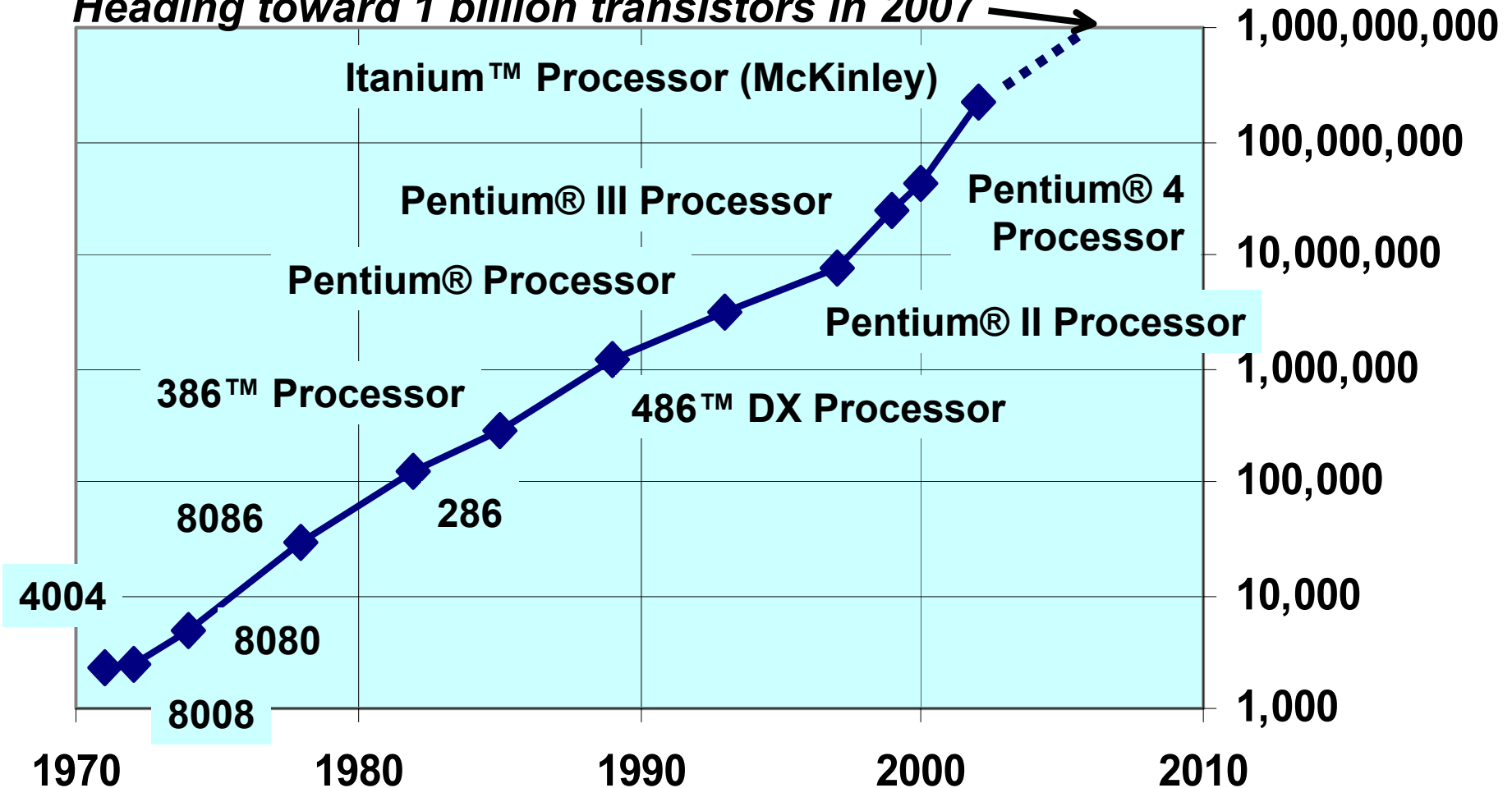
- **Introduction**
- **Manufacturing**
- **Lithography**
- **Transistors**
- **Packaging**

Our environment

- Increasing chip manufacturing complexity
- Increasing global development and manufacturing
- Continuing cost control efforts
- Increasing environmental regulations
- Growing concern about power consumption

Moore's Law

Heading toward 1 billion transistors in 2007




How does Intel operate in this environment?

- De-Centralized Research Groups
- Centralized Silicon Wafer Development
 - Logic: Hillsboro, Oregon
 - Memory: Santa Clara, California
- Copy Exactly! from development into manufacturing
 - Multiple factories, multiple countries

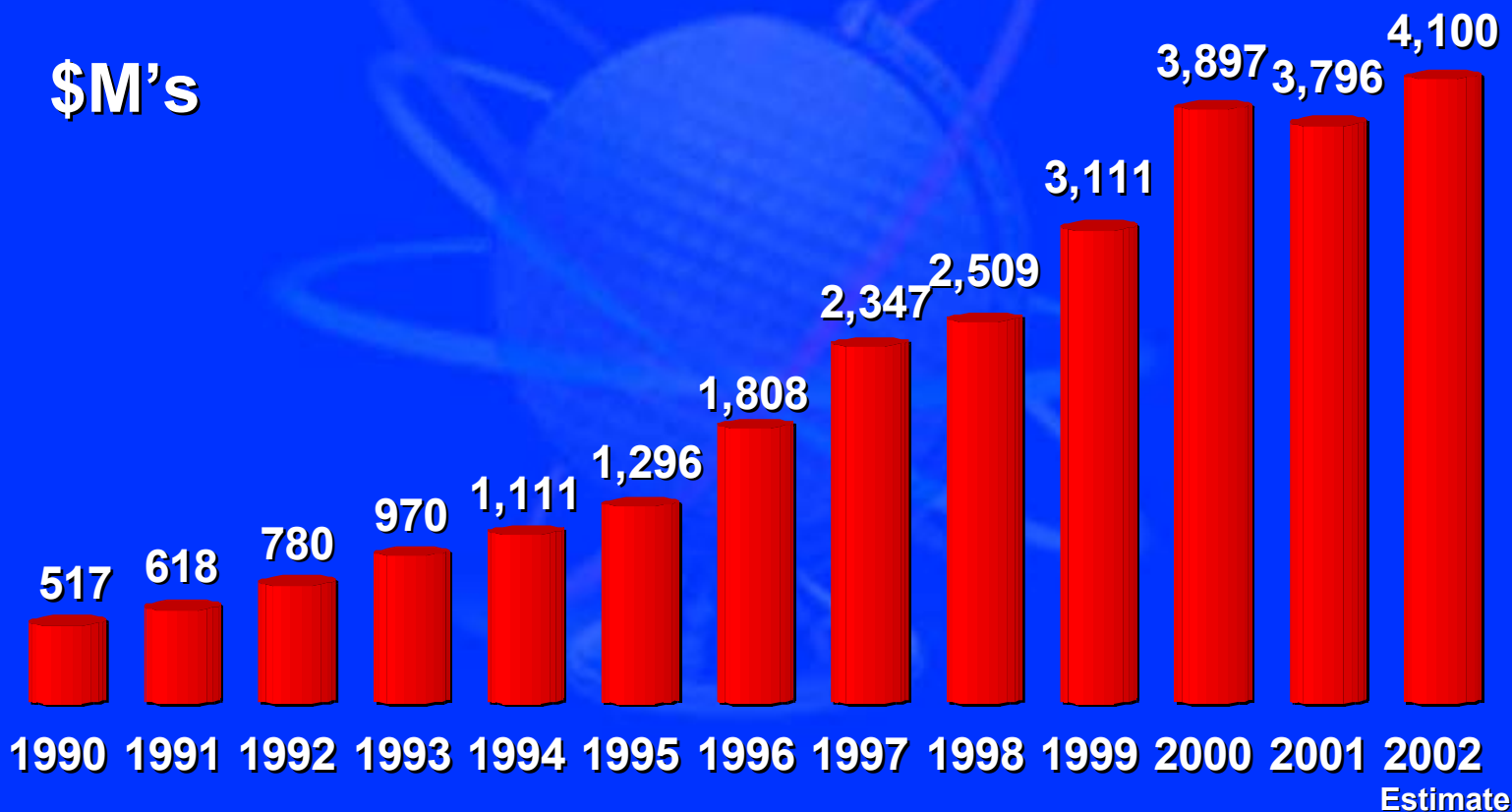
Moore's Law Drives Research Development & Manufacturing

- **New technology generation every 2 years**
 - 2x die per wafer with $\frac{1}{2}$ transistor cost
 - 2x microprocessor speed
- **Flawless ramp of new technologies into high volume manufacturing (HVM)**
 - High yields, cost-effective manufacturing
- **Introduce new products during HVM ramp**
 - Deliver best products on the best technology

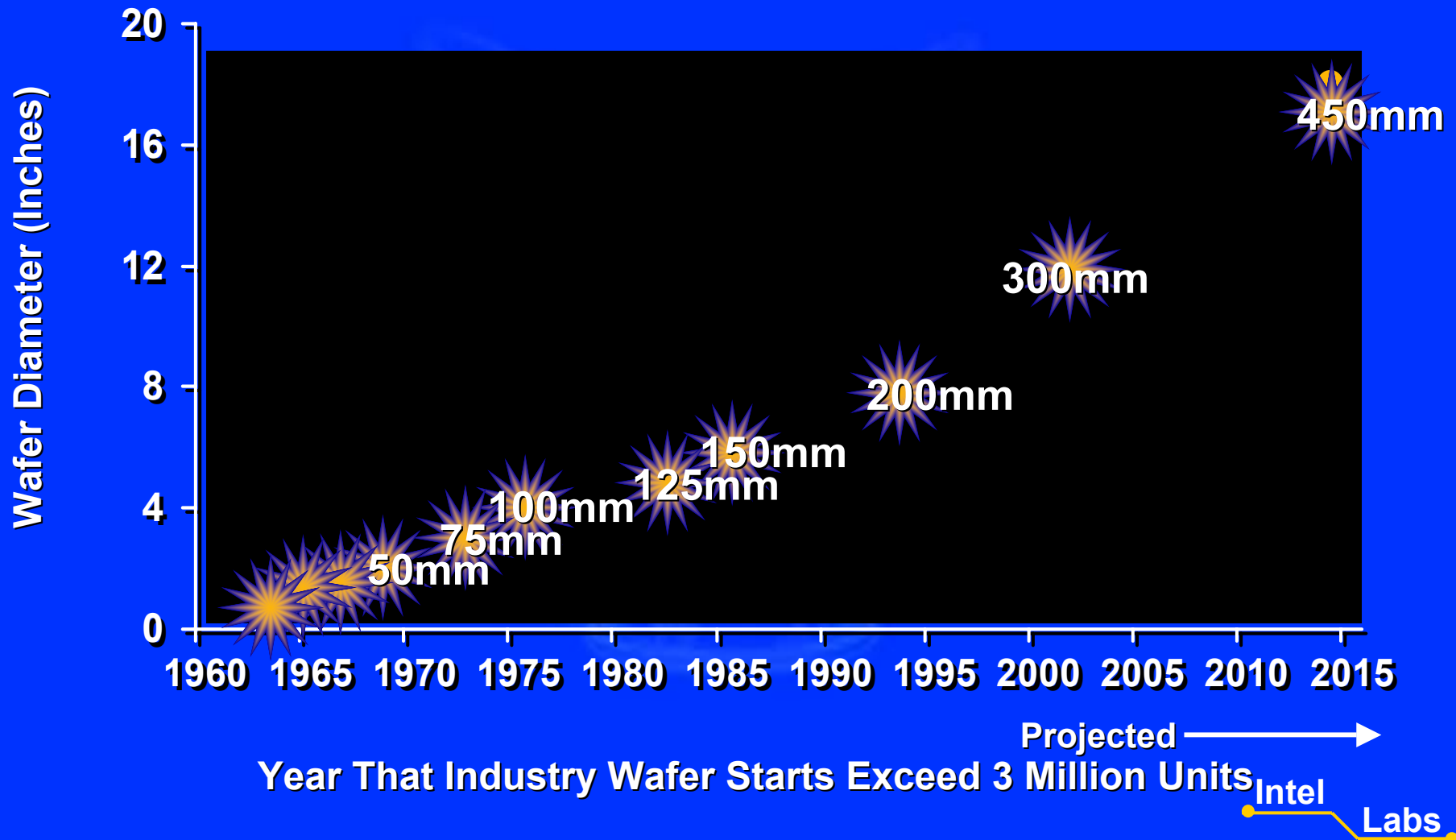
Process Evolution

	Actual				Forecast		
Process Name	<u>P856</u>	<u>P858</u>	<u>Px60</u>	<u>P1262</u>	<u>P1264</u>	<u>P1266</u>	<u>P1268</u>
1 st Production	1997	1999	2001	2003	2005	2007	2009
Lithography	0.25	0.18 μm	130 nm	90	65	45	32 nm
Gate Length	0.20	0.13 μm	65 nm	45	32	22	16 nm
							
	Fab		Development		Research		

Huge R&D Investment

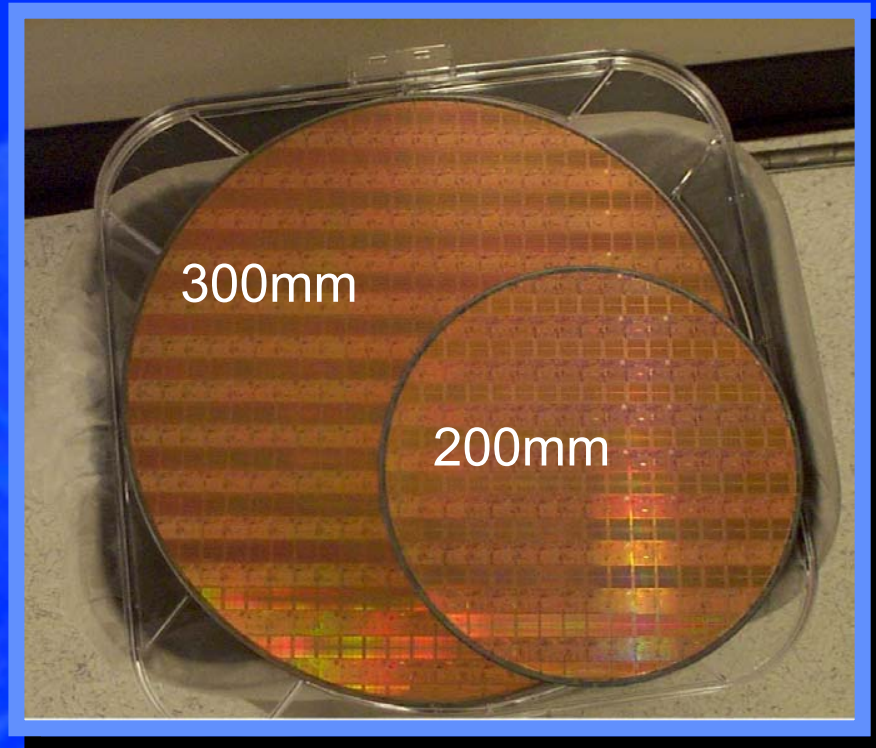


Wafer Size Transitions



300mm Wafer Transition

March 2001:
First fully functional
300mm wafer on
0.13 μ m technology



Capacity and Cost Benefits:
240% more die/wafer
30% lower cost per die
40% less energy and water per die

Moore's Law + 300mm Wafers = 4x advantage

- **Moore's Law:**
 - From 0.18 μm to 0.13 μm = 2x transistor density
- **300mm Wafers:**
 - From 200 mm to 300 mm = 2.4x silicon area
- **Combined output advantage:**
 - > 4x output per factory vs 0.18 μm on 200mm

300mm Automation



**Multilevel automated
material handling system**

**Overhead hoist vehicle (OHV)
and “FOUP” (wafer box)**



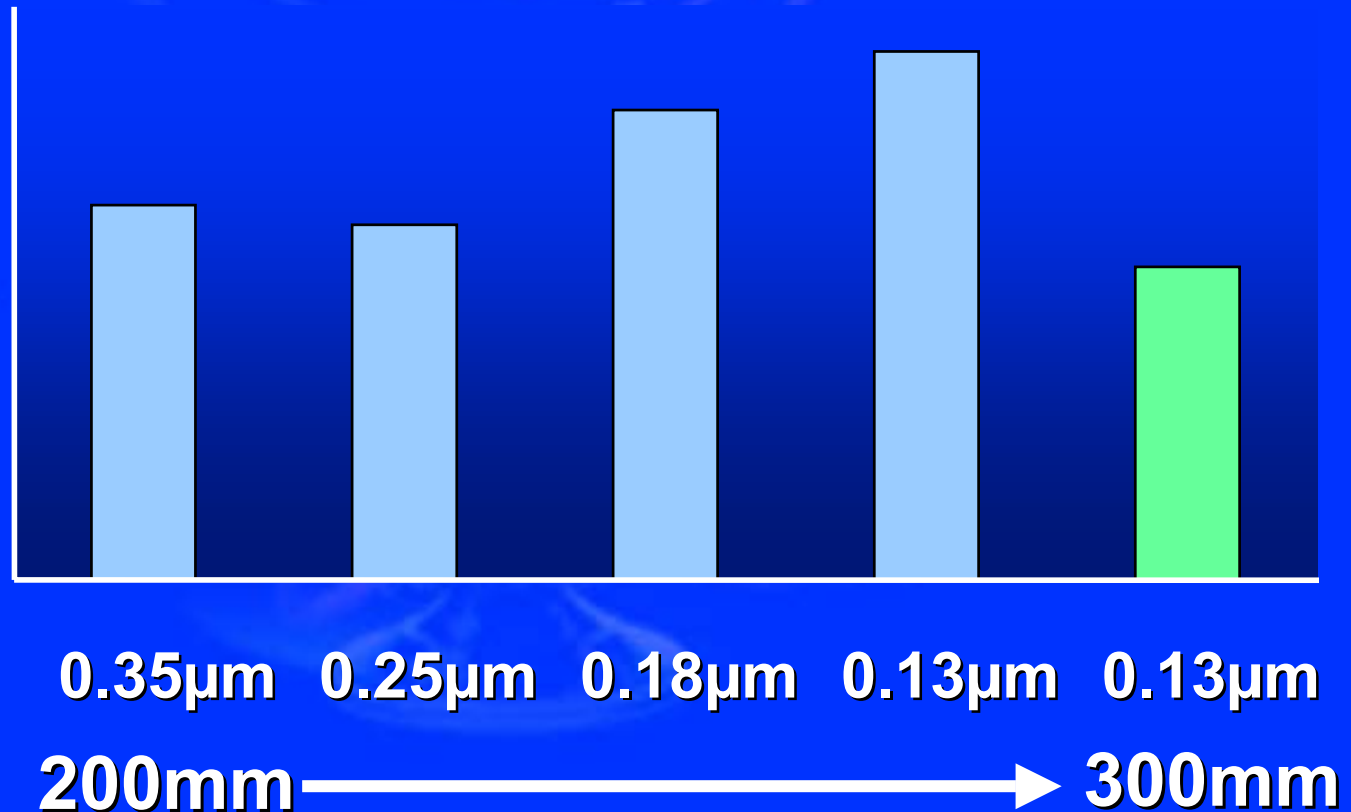
OHV

FOUP

S

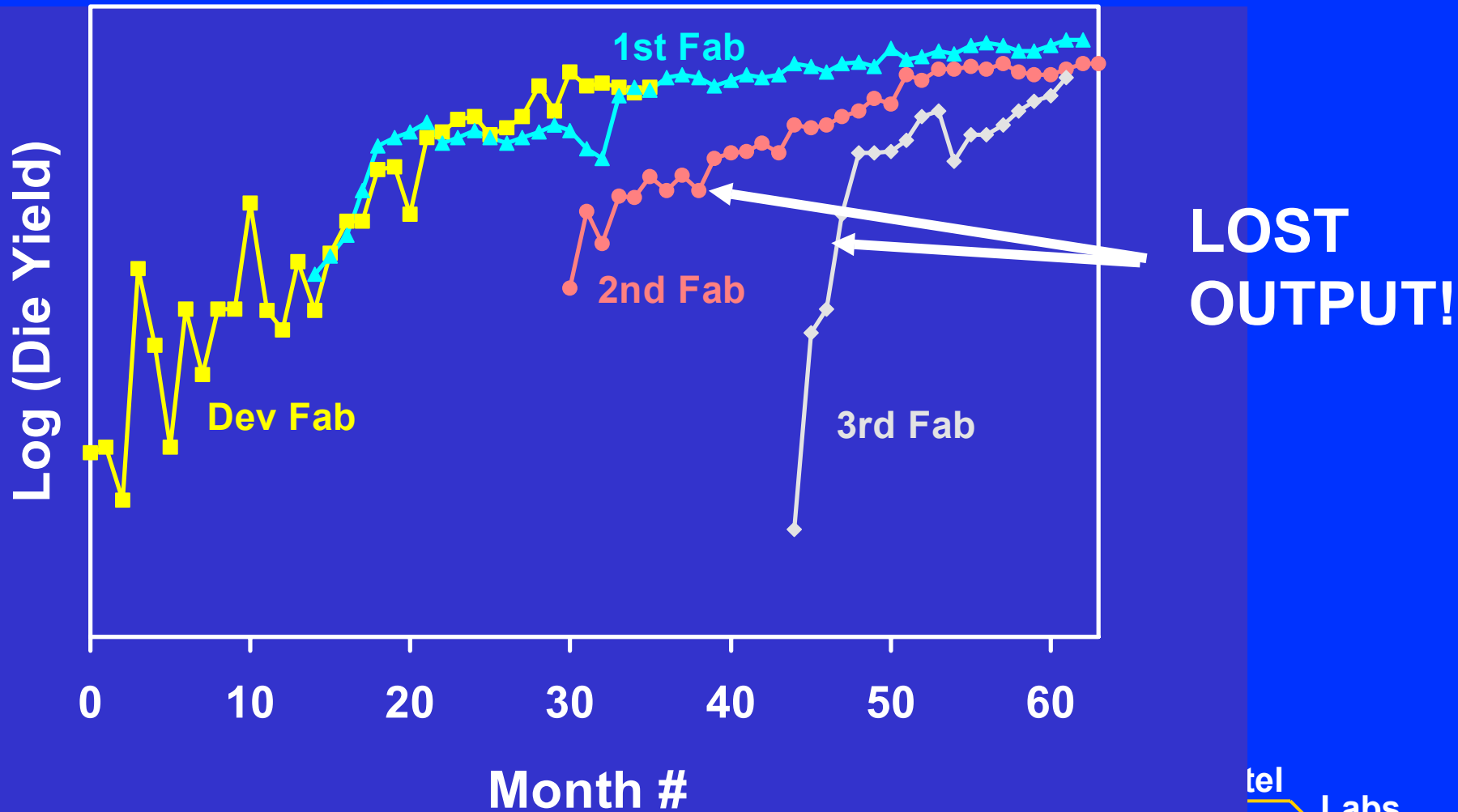
300mm Rolls Cost Back

Capital cost
per unit
wafer area



The Birth of Copy Exactly!

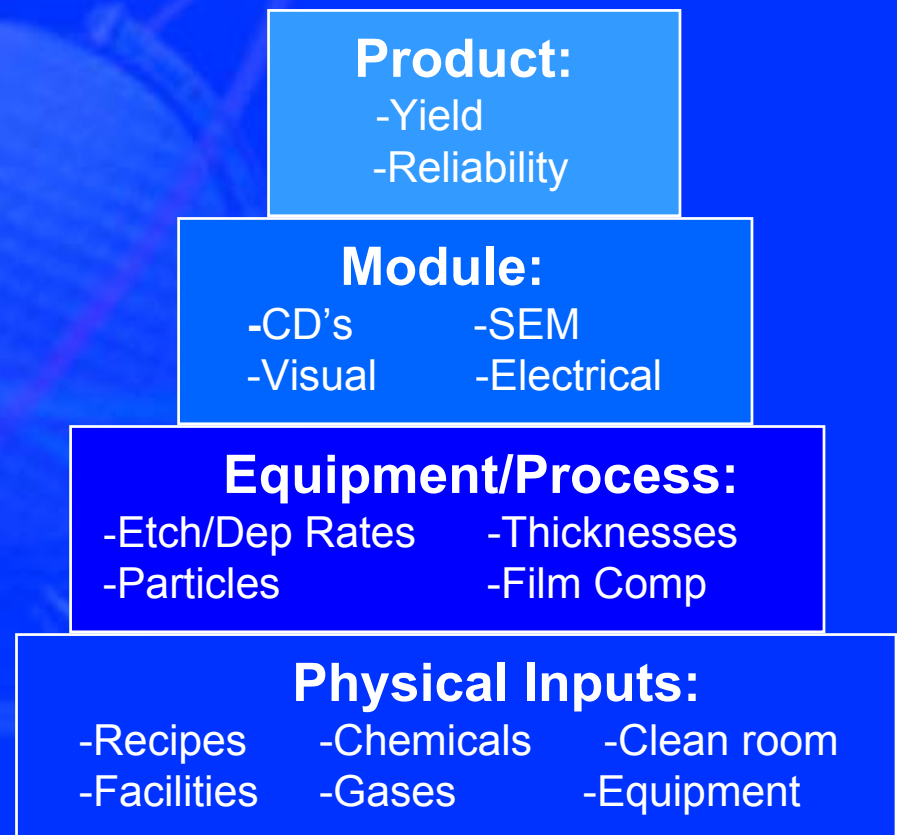
Intel 1 μ m Process



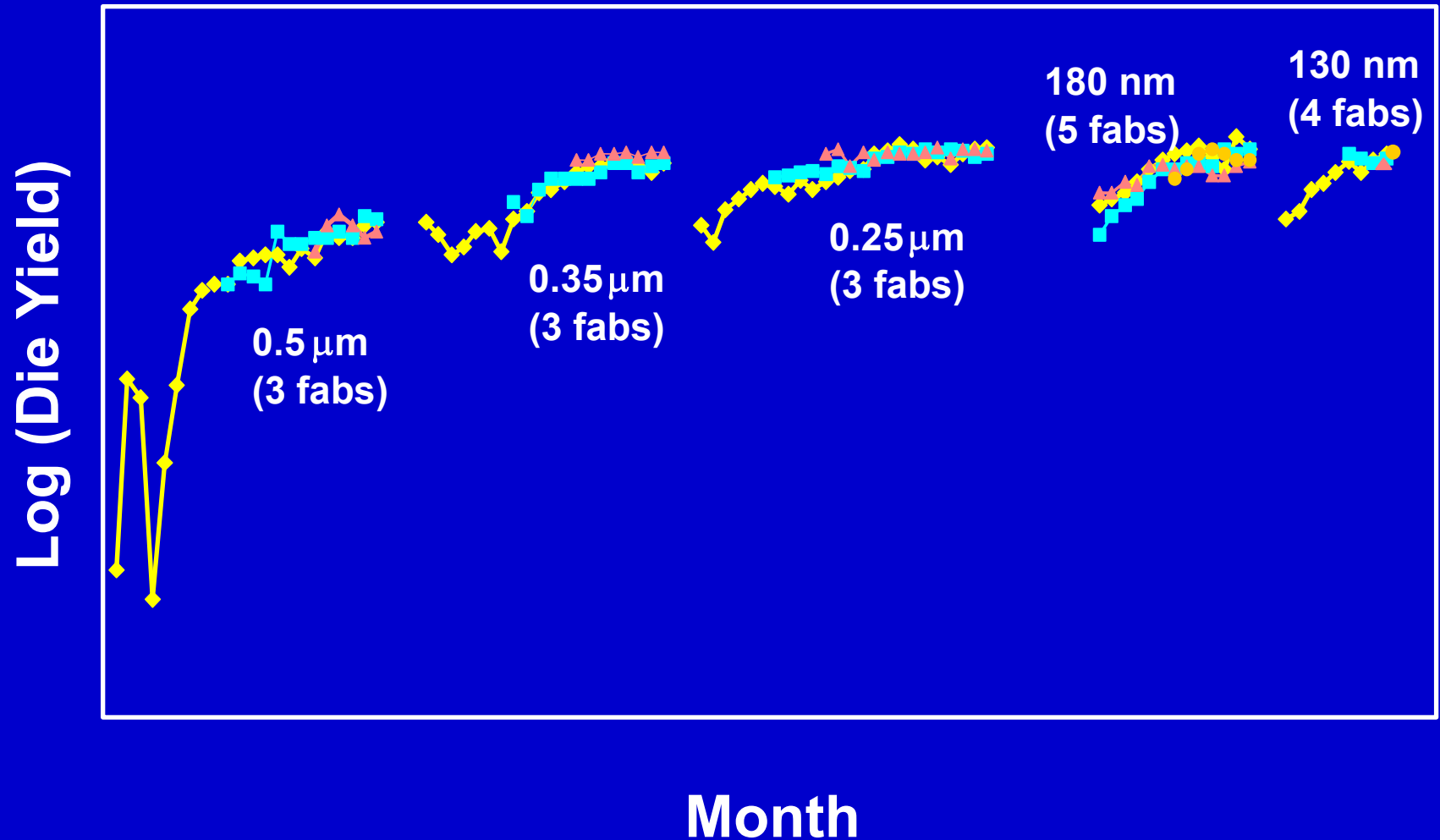
**LOST
OUTPUT!**

Copy Exactly! Method

- **Matching at all levels**
 - same physical inputs
 - statistically matched responses (outputs)
- **Keeping matched**
 - coordinated changes
 - audits
 - process control system
 - joint fab mgmt structure

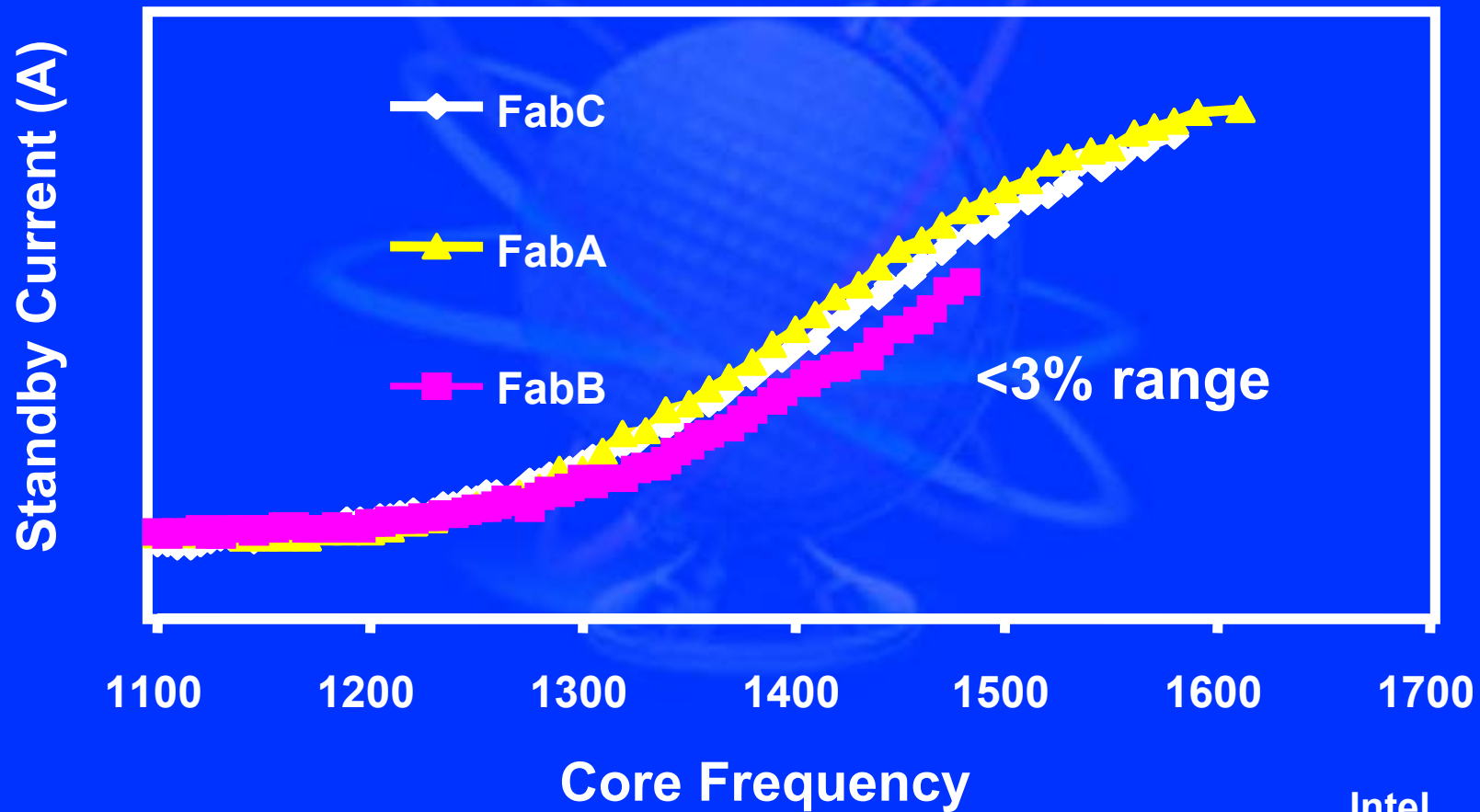


200mm Yield Matching



130nm Tech Performance Matching

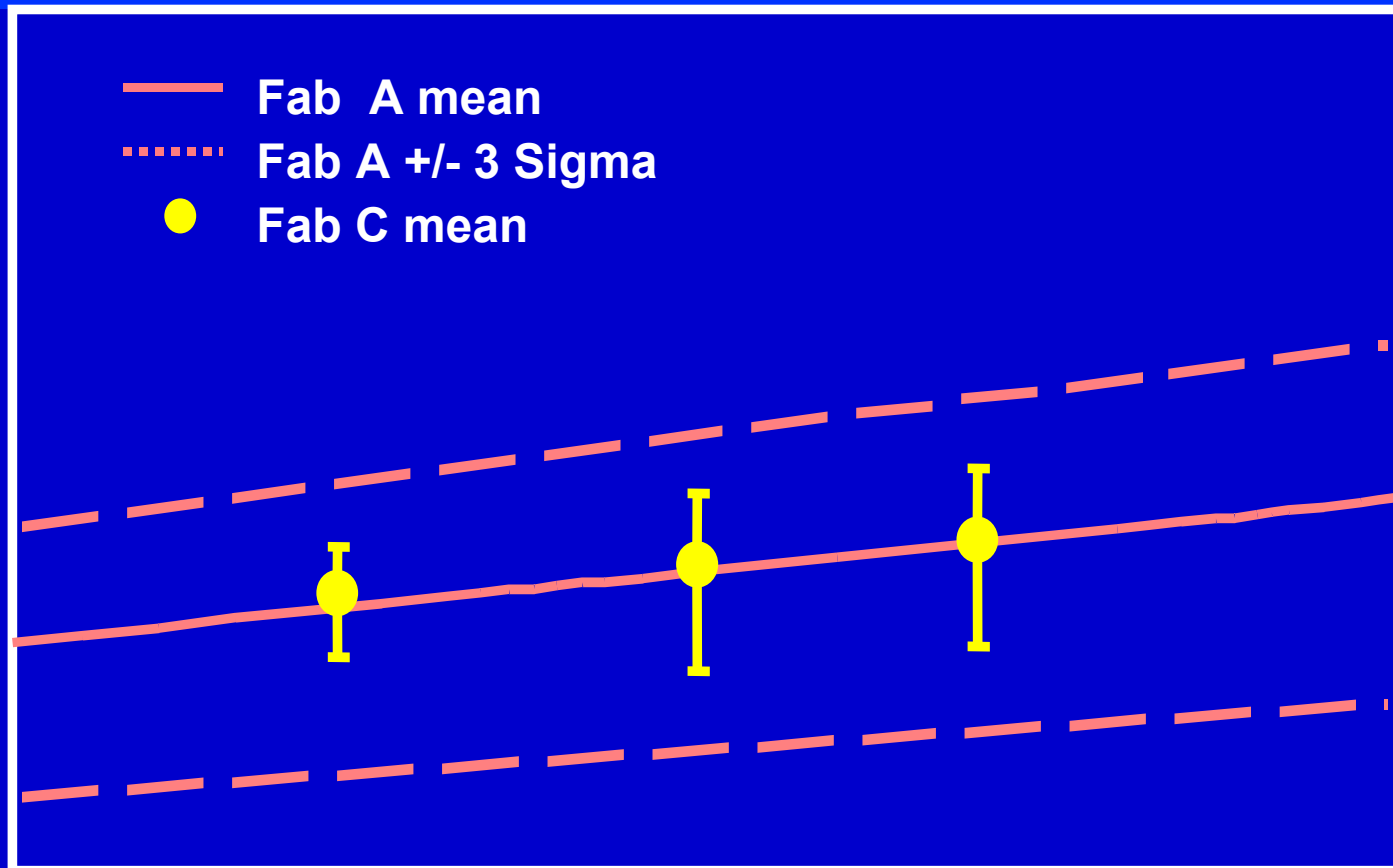
Pentium® III processor frequency



130nm Tech Reliability Matching

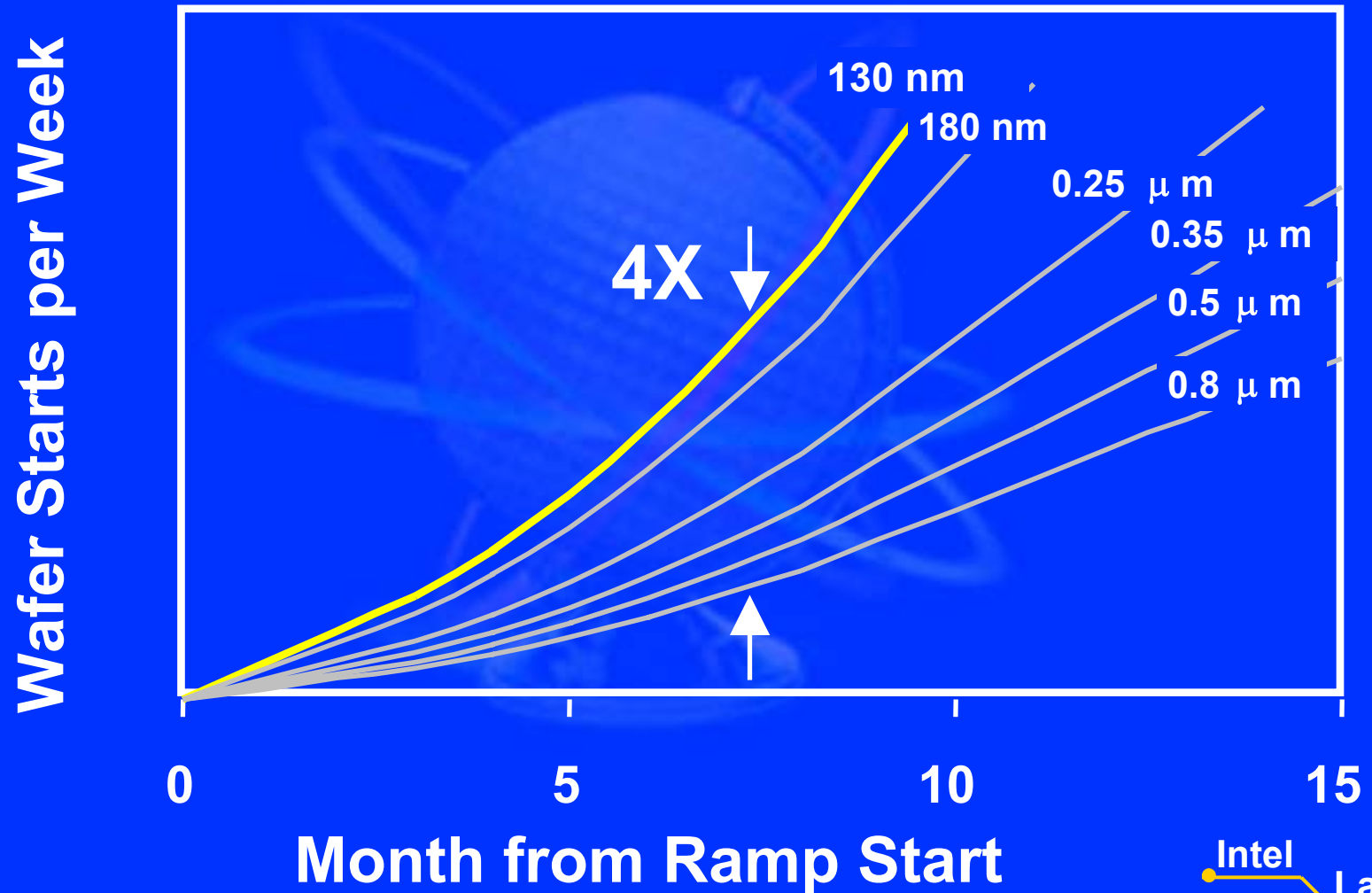
Pentium® III processor burnin

Cumulative fail rate
[normal probability scale]

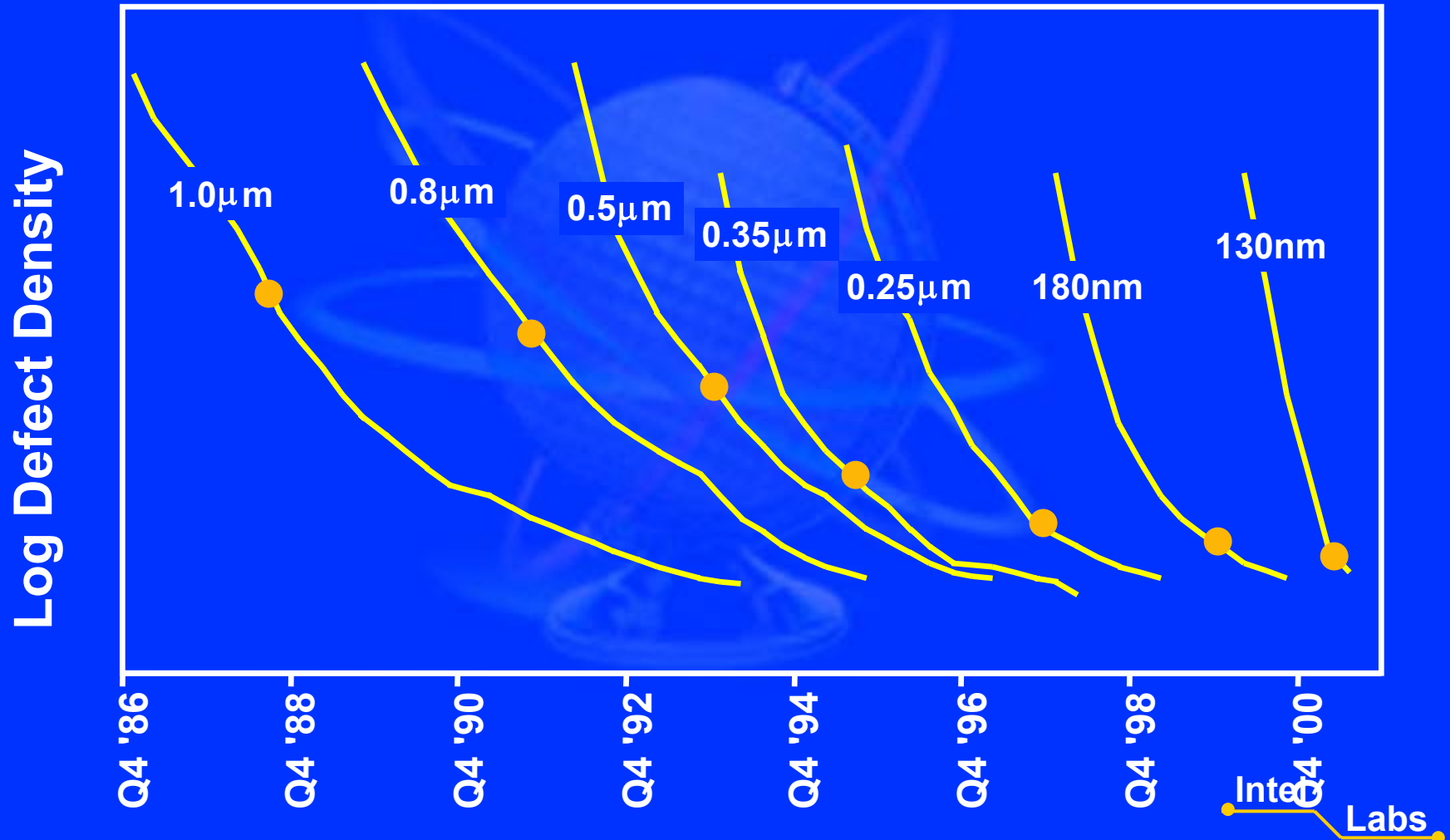


Relative stress time [log scale]

Manufacturing Ramp Rates Improving



Yield Learning Rates Improving

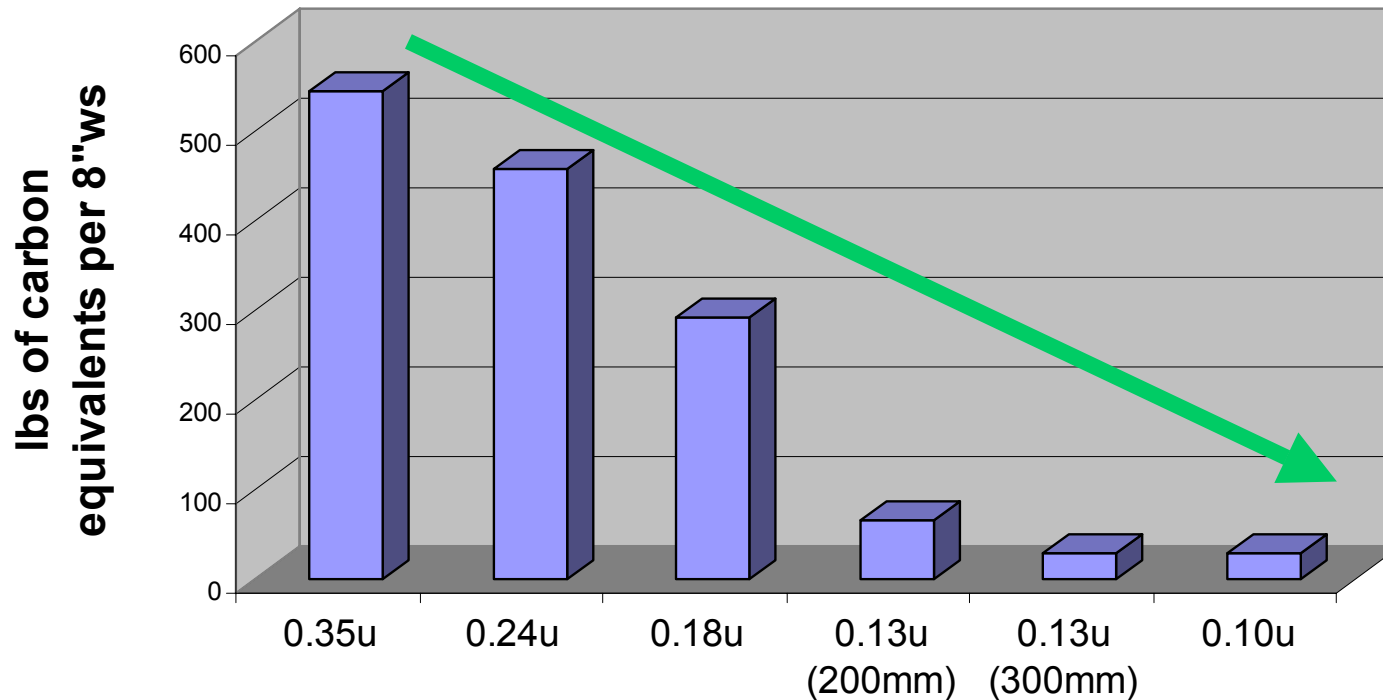


Intel's Environmental Methodology

- Research group demonstrates feasibility of new chemicals and equipment
- Manufacturing tools, chemicals, and process recipes are finalized during development process
 - Emissions and environmental data is incorporated into the manufacturing tool selection process
- Development process is transferred using Copy Exactly! into all manufacturing sites

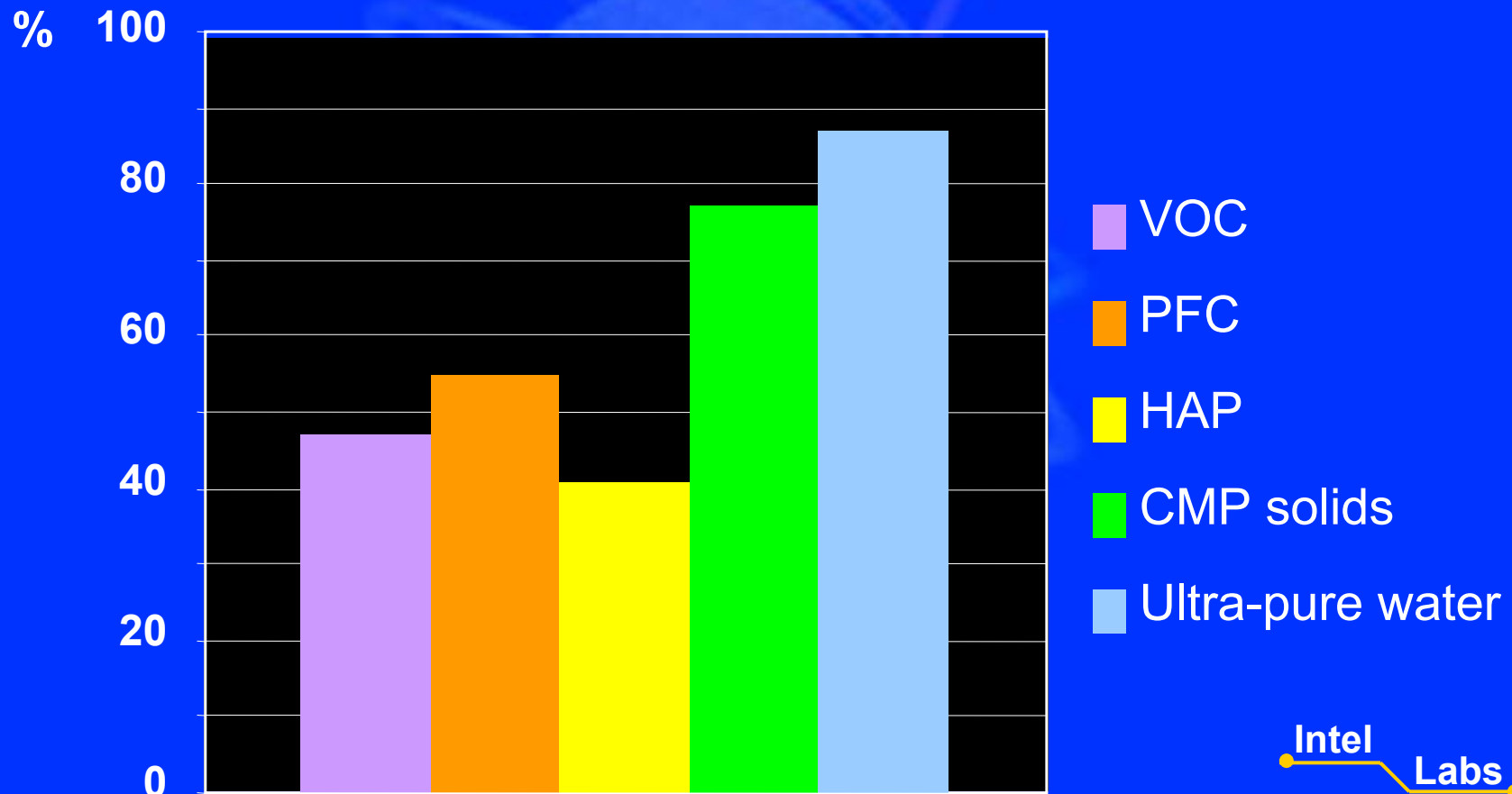
95% Reduction in Emissions per Silicon Area

PFC Process Emissions Trend



300mm Tools are More Chemically Efficient

Estimated 300mm emission / consumption
relative to 200mm (per unit silicon area)



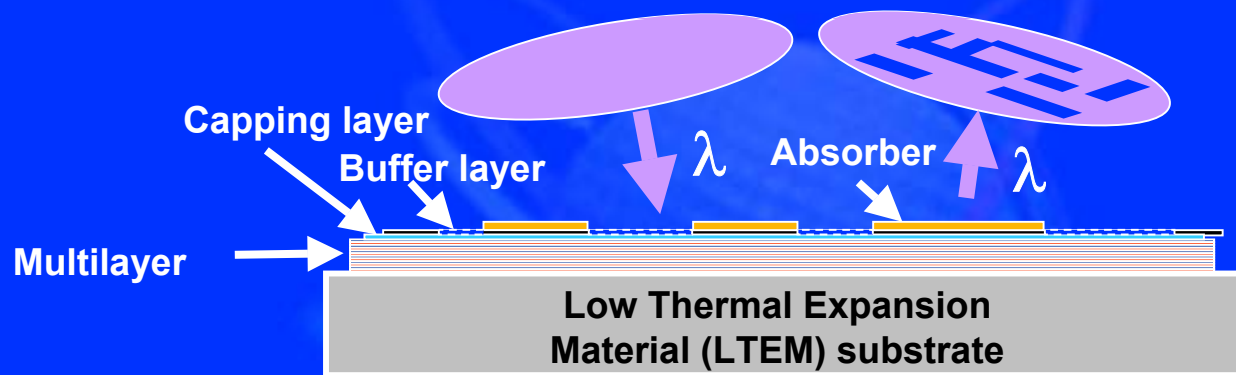
Intel Delivers

- **High volume manufacturing of Intel's most advanced technologies is one of Intel's strategic advantages**
- **300 mm output capacity will help distance Intel from our competitors**

Lithography

- **Challenge: cost effective way to print smaller dimensions**
- **One Research Approach:**
 - **Shrink wavelength of exposure light**
 - 248 nm wavelength manufacturing
 - 193 nm wavelength development
 - 157 nm wavelength pathfinding
 - 13 nm (EUV) wavelength research

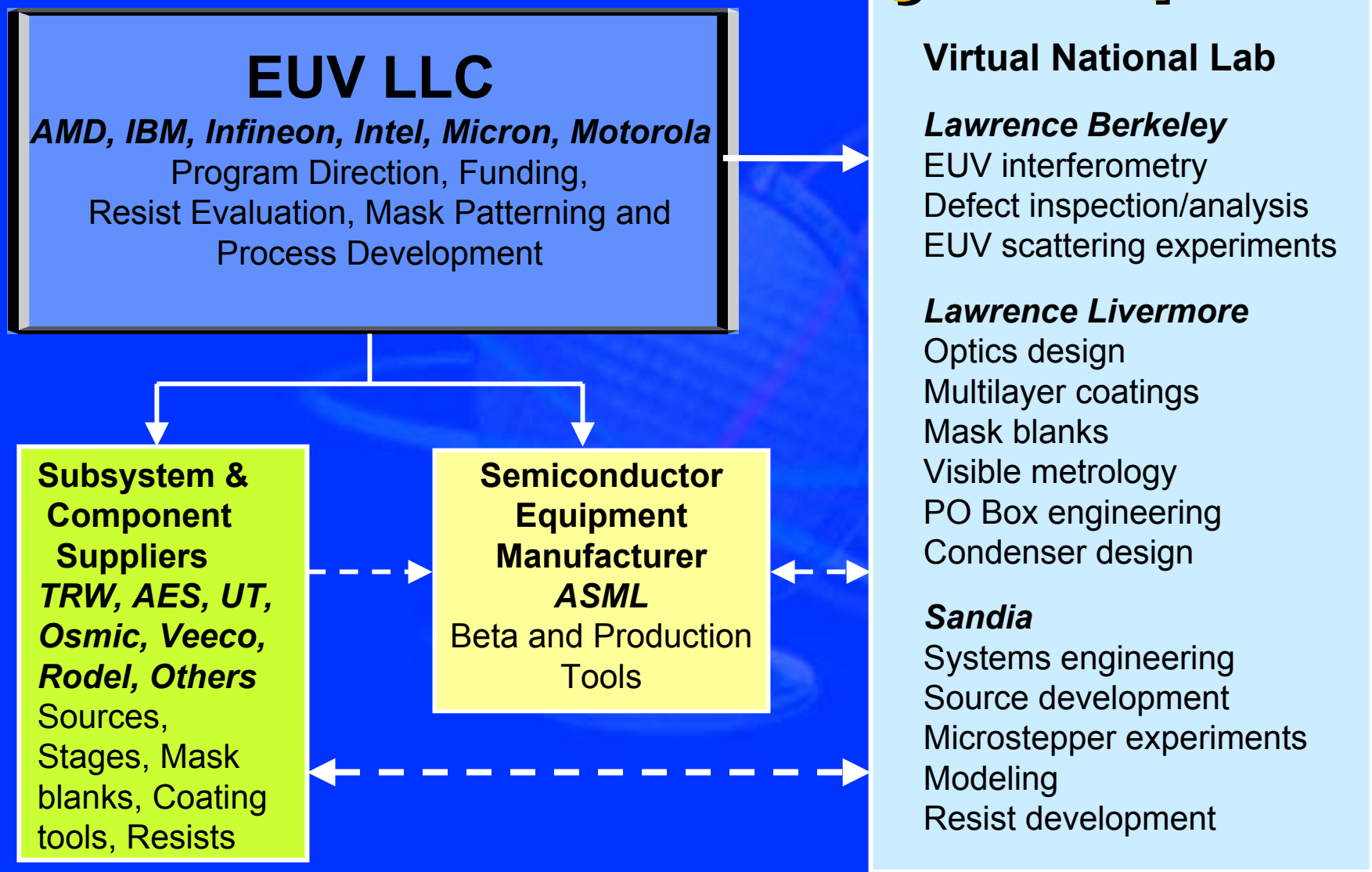
EUV is a disruptive technology



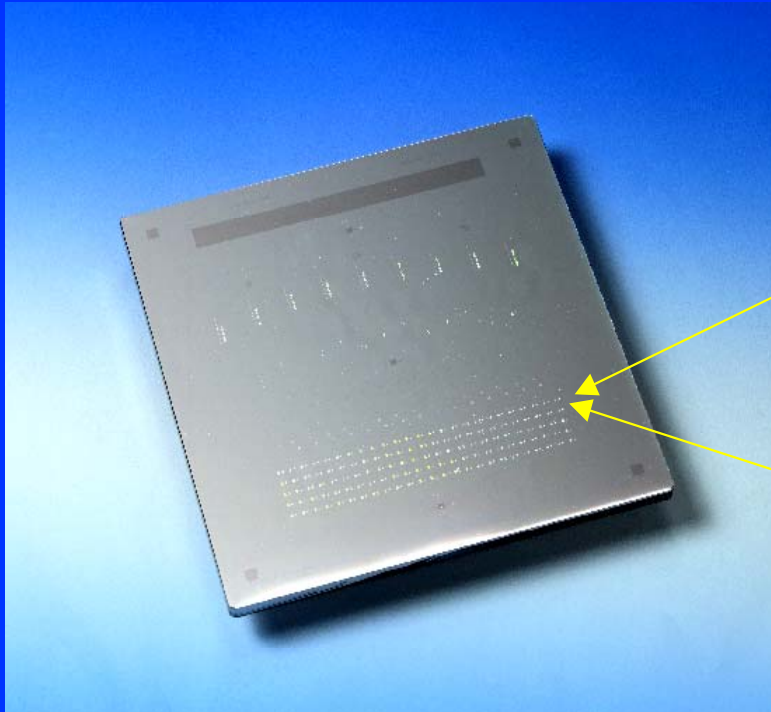
Mask Structure with incident and reflected EUV

EUV light does not transmit through glass or air

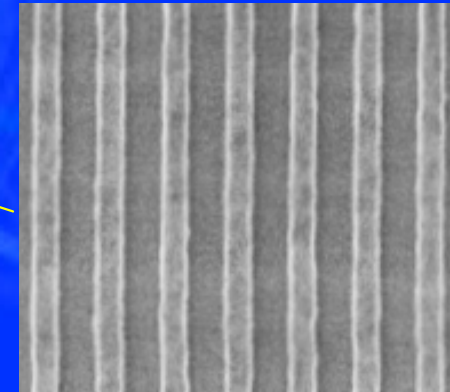
EUV Limited Liability Corp.



Intel Delivers World's First 6" EUV Mask

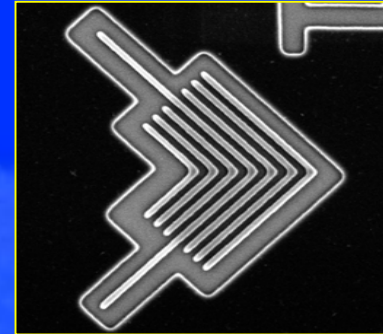
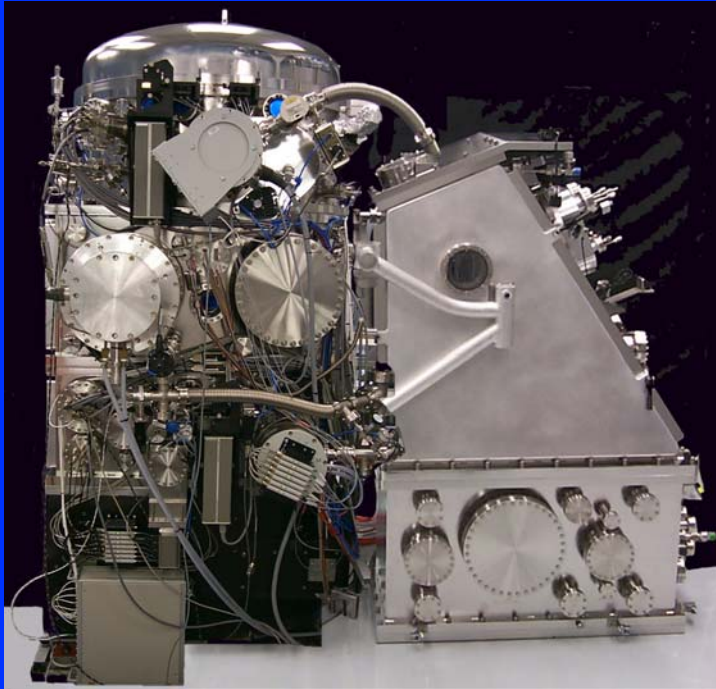


120 mm x 104 mm field size

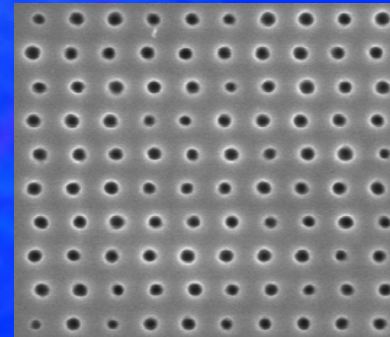


200 nm lines/spaces for 50 nm node

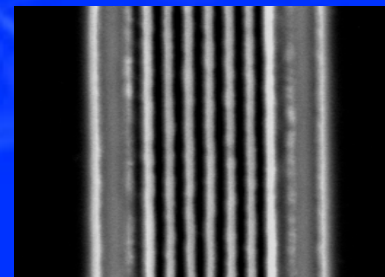
EUV Optics Upgrades



100 nm
 $k_1 = 0.75$
($\sigma = 0.8$)



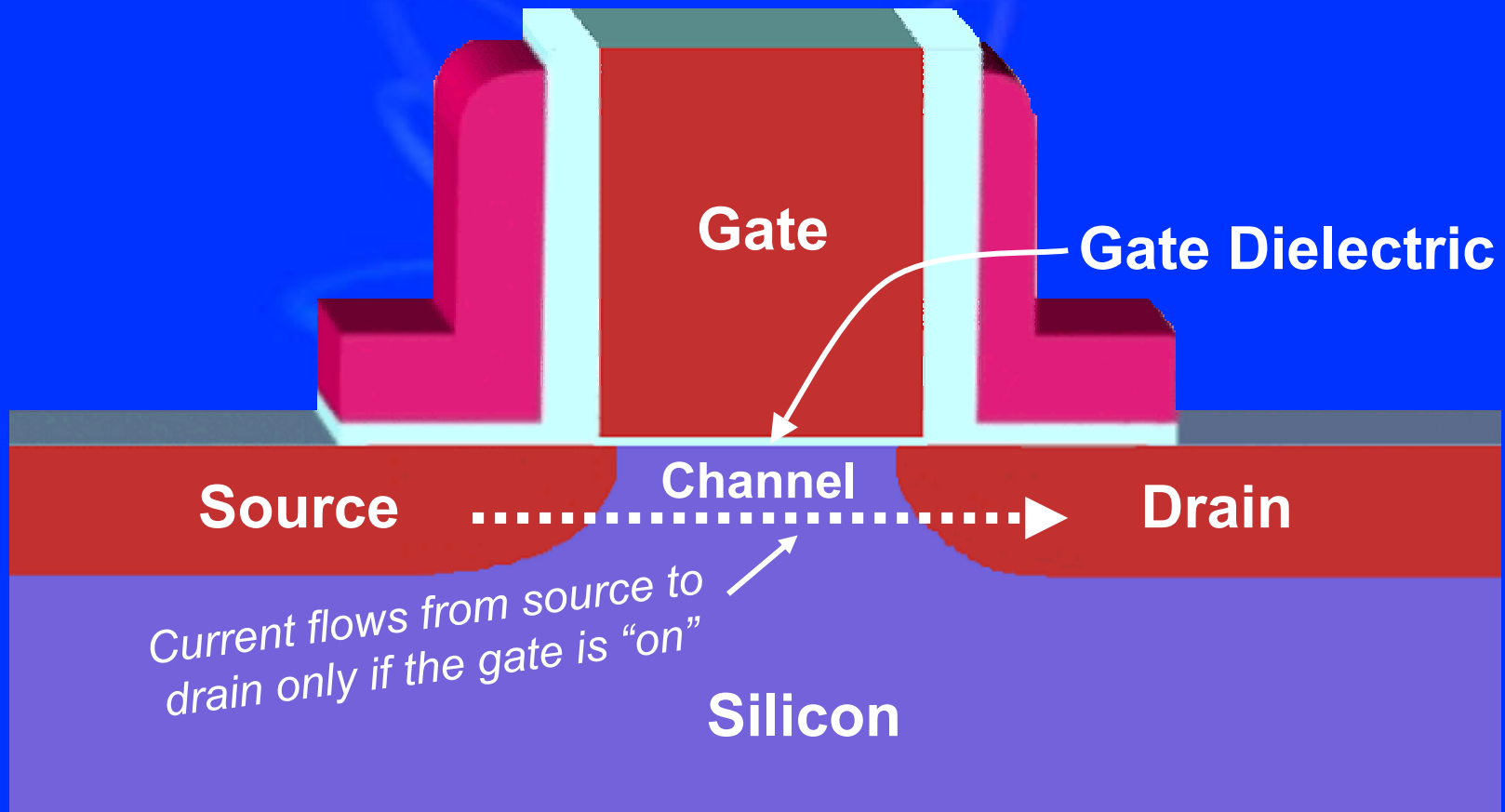
70 nm
($\sigma = 0.8$)



50 nm dense
 $k_1 = 0.37$,
Dipole
illumination

EUV Prototype in Livermore CA

Close-up of a CMOS transistor

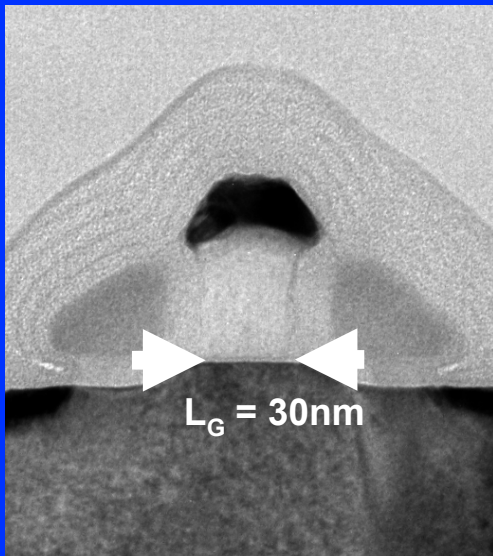


Transistors Keep Shrinking

Record small transistors produced in Intel Labs

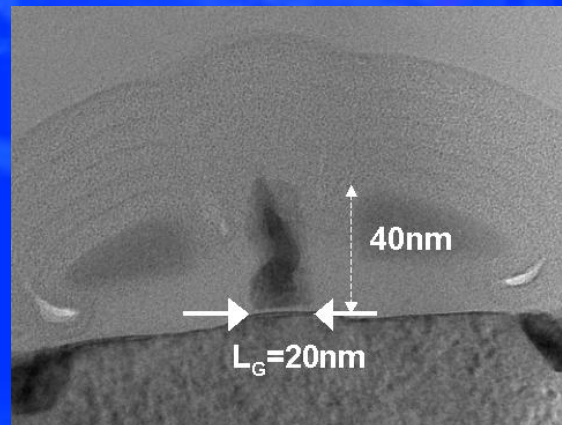
Intel Developer Forum
Spring 2002

30 nm



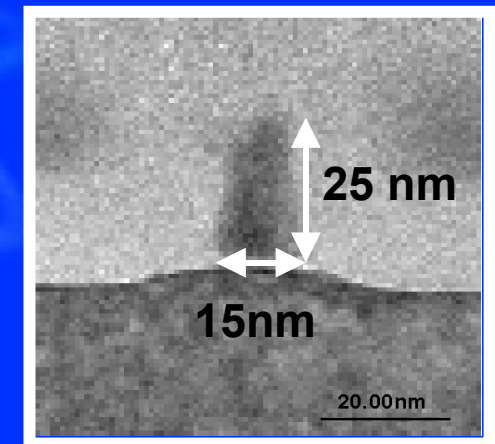
December 2000

20 nm



June 2001

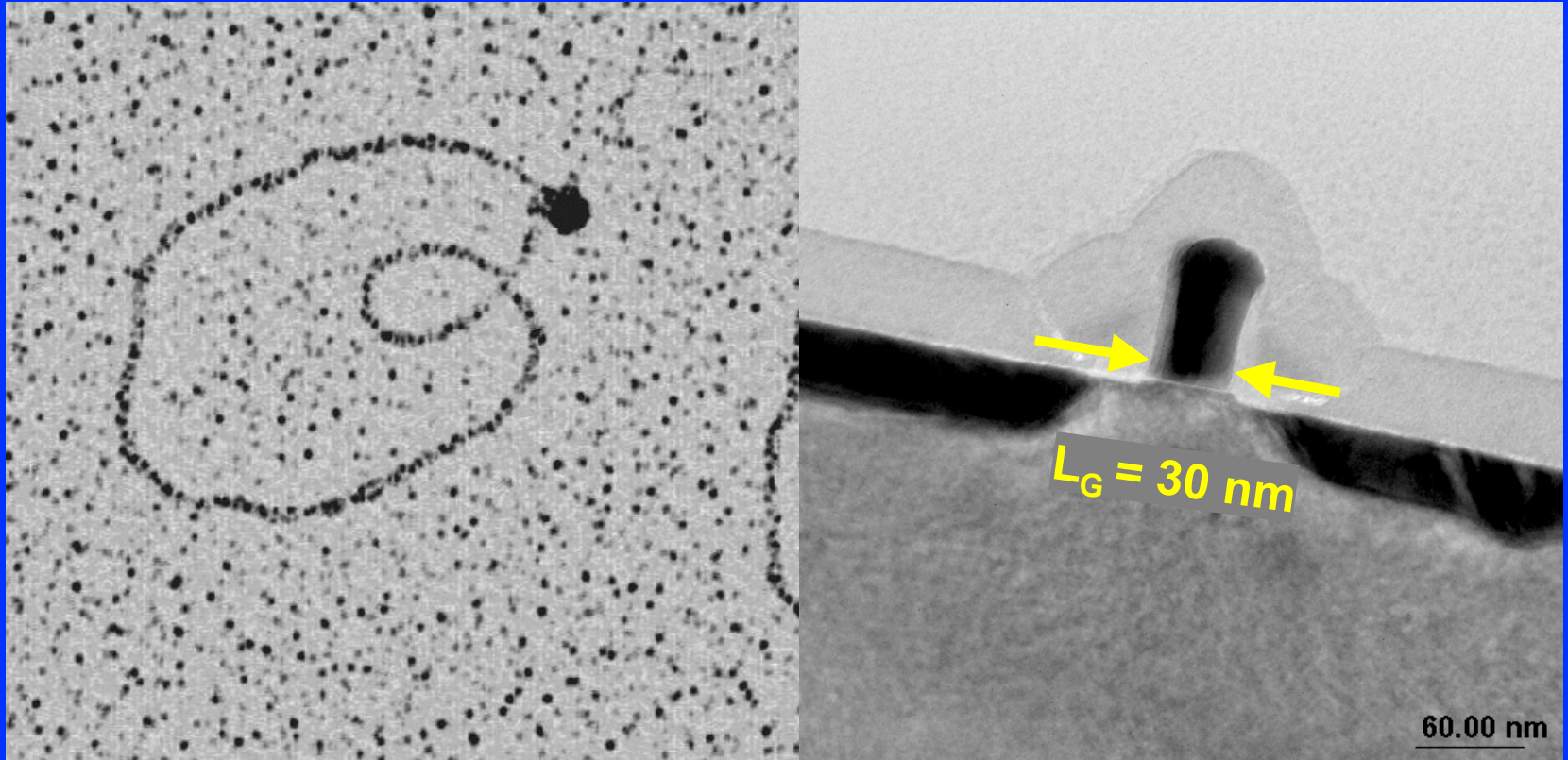
15 nm



December 2001

Intel Labs

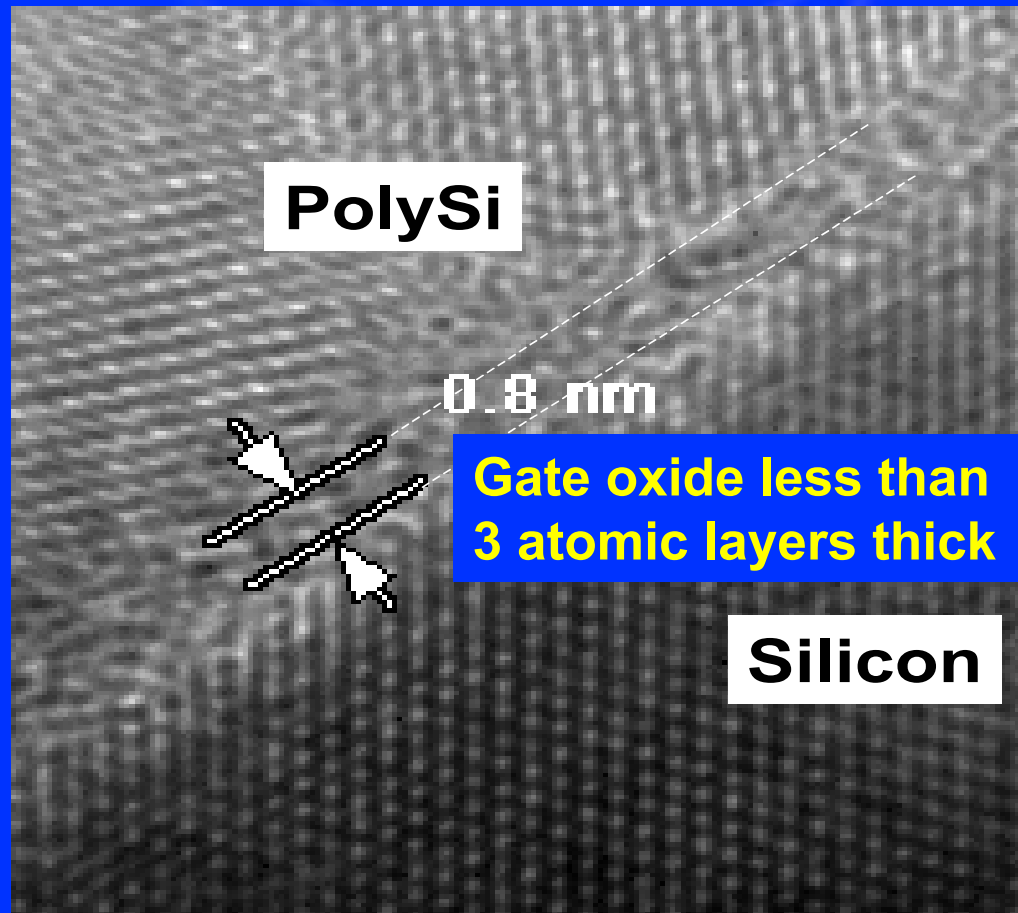
Transistors as Small as DNA



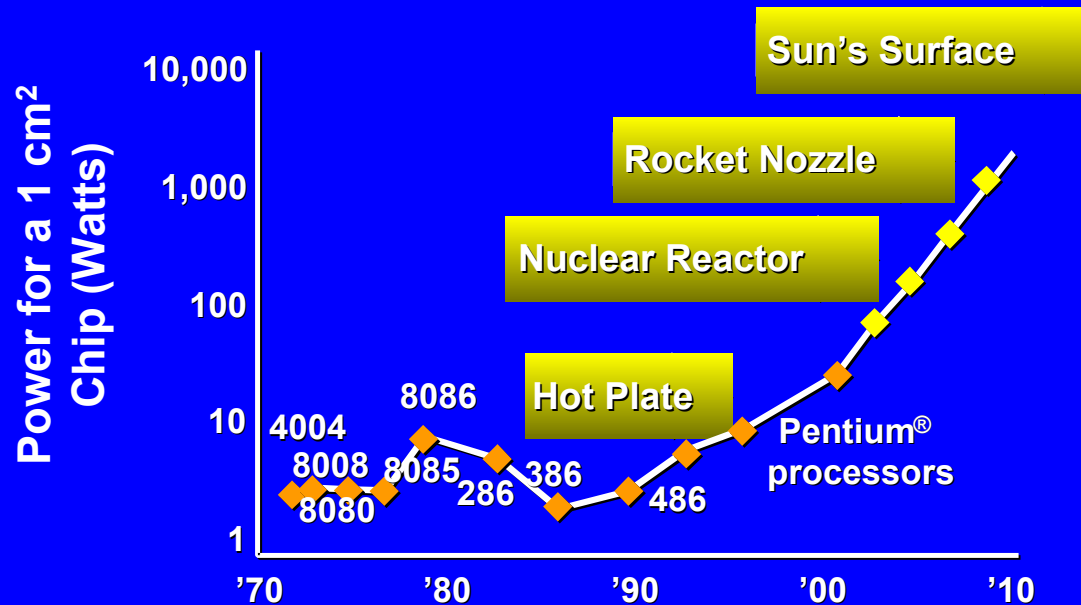
10 nm gold particle attached to Z-DNA antibody
[John Jackson & Inman. *Gene* 198984-226]

30 nm gate length ($L_G=30$)
Intel Research Transistor

Gate Oxides as Thin as Atoms



A Big “New” Problem



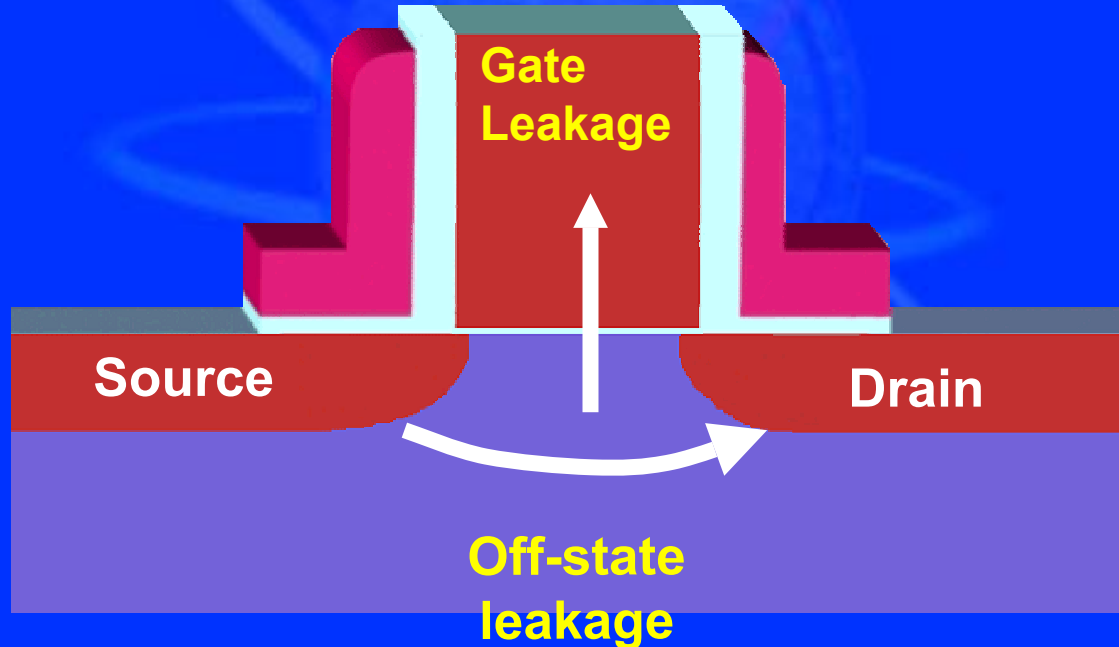
Pat Gelsinger's Slide from ISSCC 2001

*If nothing is done to reduce power,
Moore's Law will be at risk*

Transistor Challenge

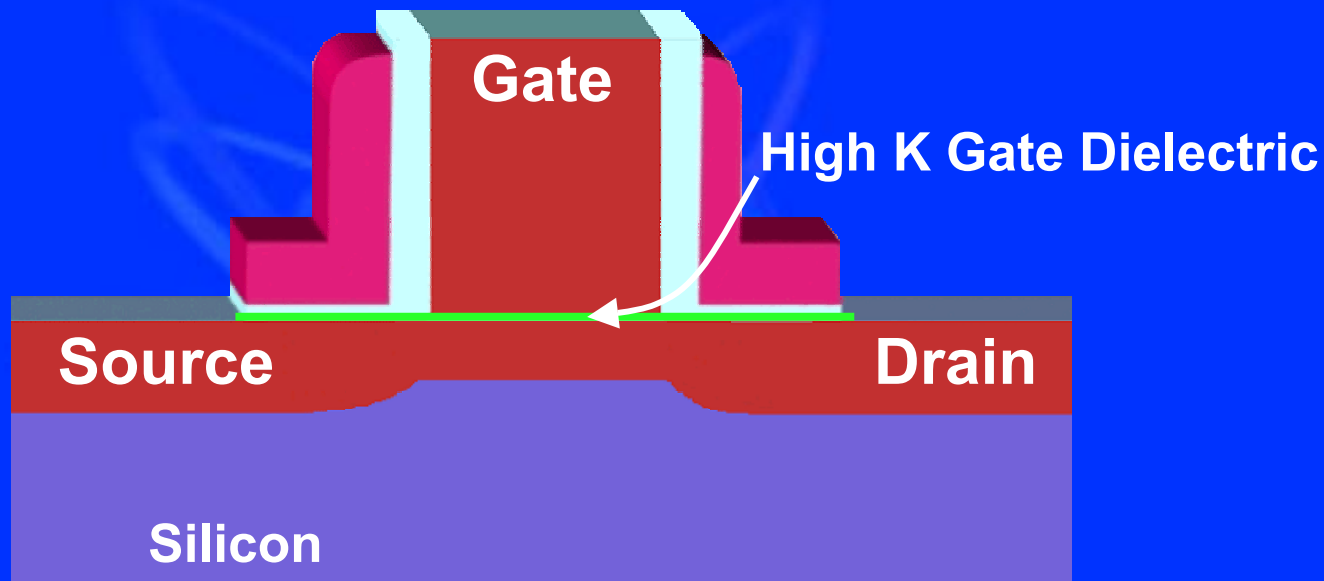
- Continue Moore's Law without Exponential increase in Power Consumption
- Intel introduced two important technologies at IEDM :
 - Depleted Substrate Transistors
 - High K gate dielectric
- Our long term approach is called:
TeraHertz Transistors

Current Leakage is a Major Problem



Gate Leakage Solution

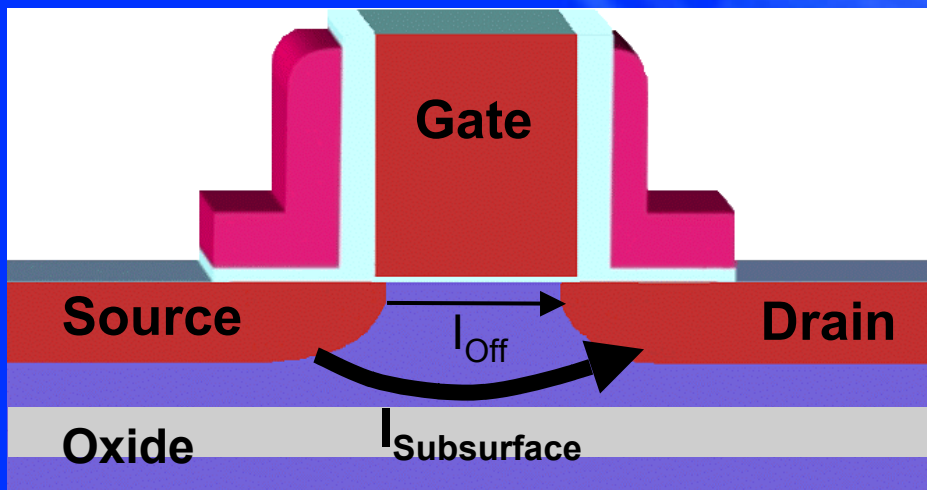
High K Gate Dielectric



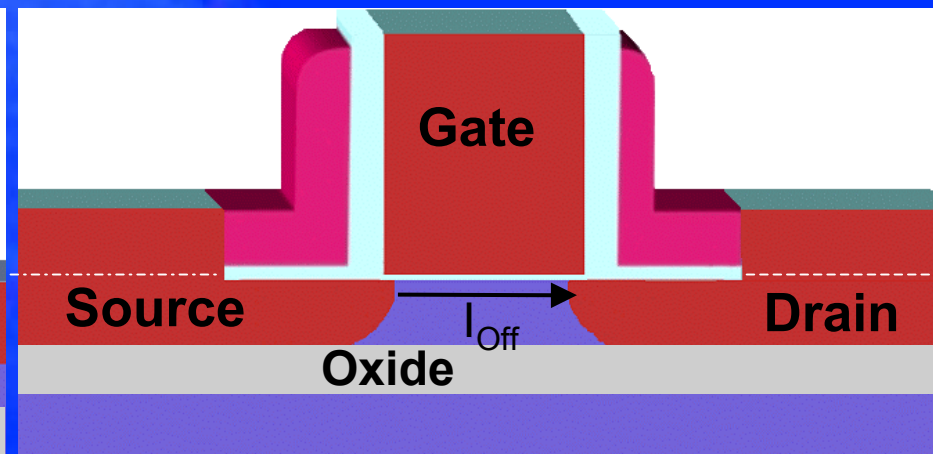
High K gate dielectric

- New material replaces silicon dioxide
- 10,000x lower leakage current through gate dielectric

DST Eliminates Leakage Paths Through Substrate



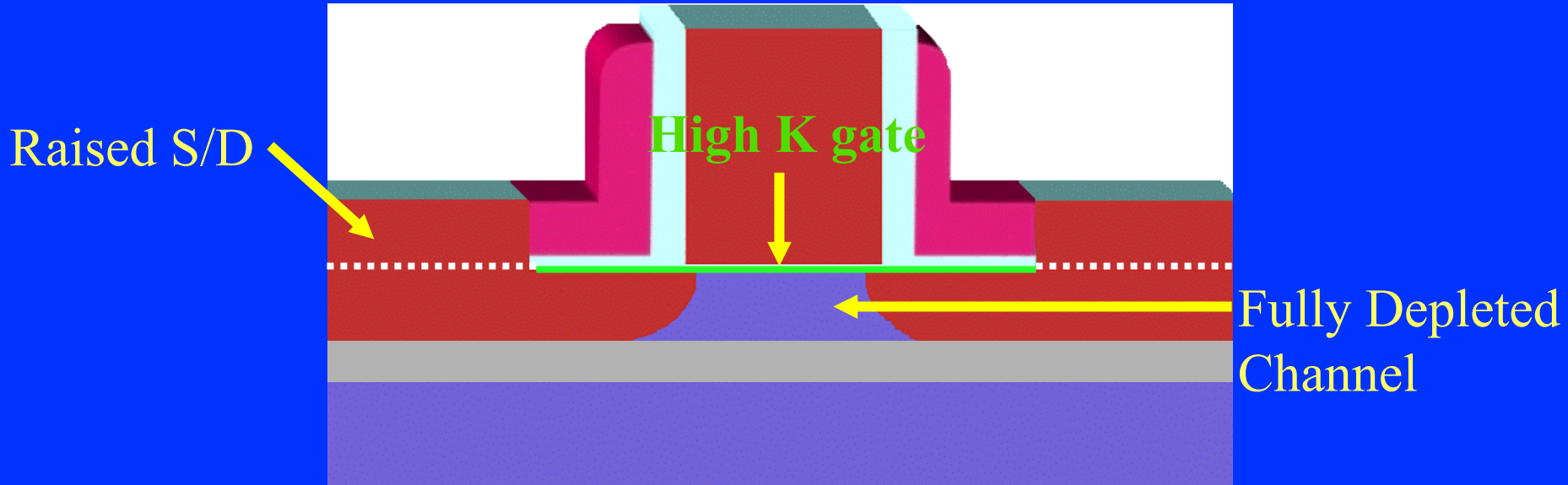
Partially Depleted SOI



DST

PD SOI has same I_{off} performance as bulk Silicon

TeraHertz Transistor Architecture



- **10,000X reduction in gate leakage**
- **100X reduction in subthreshold leakage**
- **Eliminates floating body effect**
- **Minimizes soft error rates**
- **50% lower junction capacitance than PD SOI**

Transistors

- **Transistors drive IC performance**
 - Transistor progress has accelerated
 - Intel has highest performance transistors in manufacturing and research
- **We have not found a device physics limit to making smaller and faster transistors**
 - Power, not speed is the issue for this decade

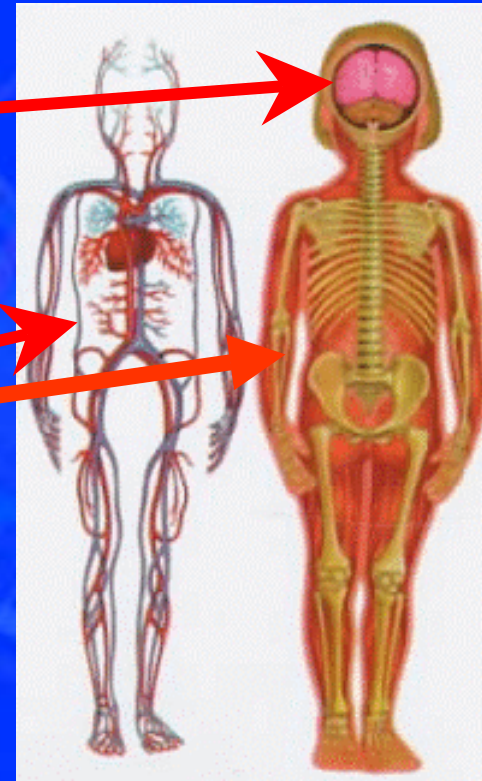
Why is packaging important?

Silicon Processor:

The “brain” of the computer

Packaging:

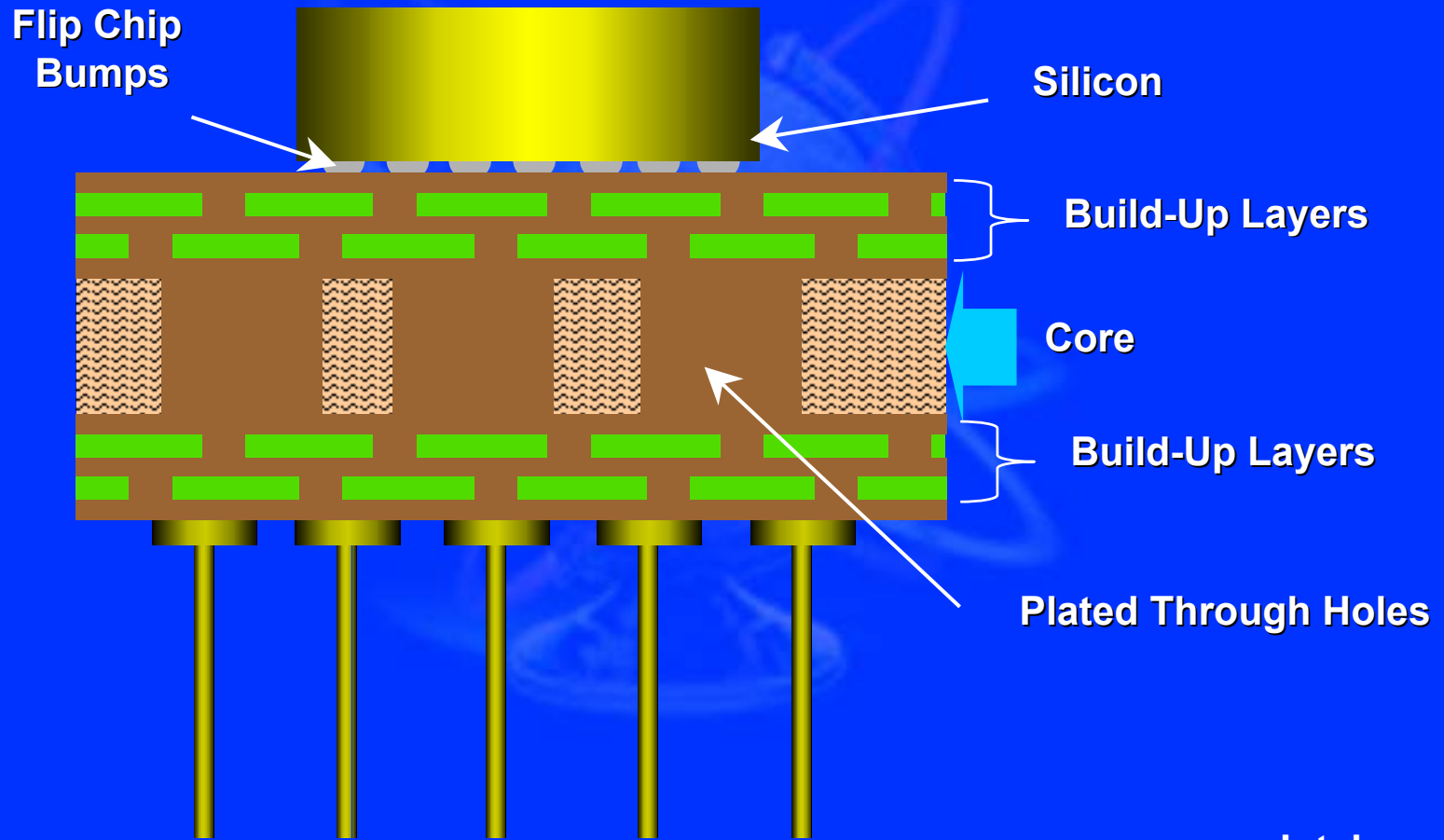
The rest of the body



***Putting Fast Silicon in a Slow Package is like
Putting a V-8 Engine in a Yugo***

Today's Microprocessor Package

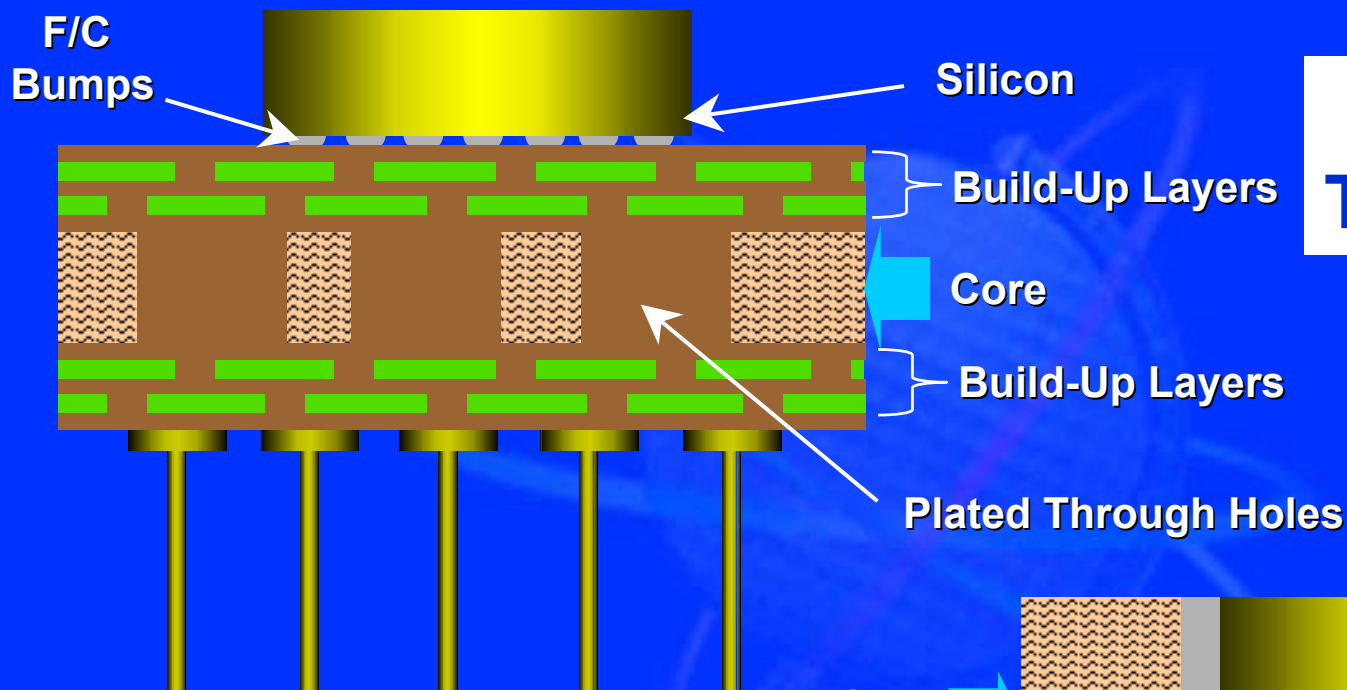
Intel
Developer
Forum
Spring 2002



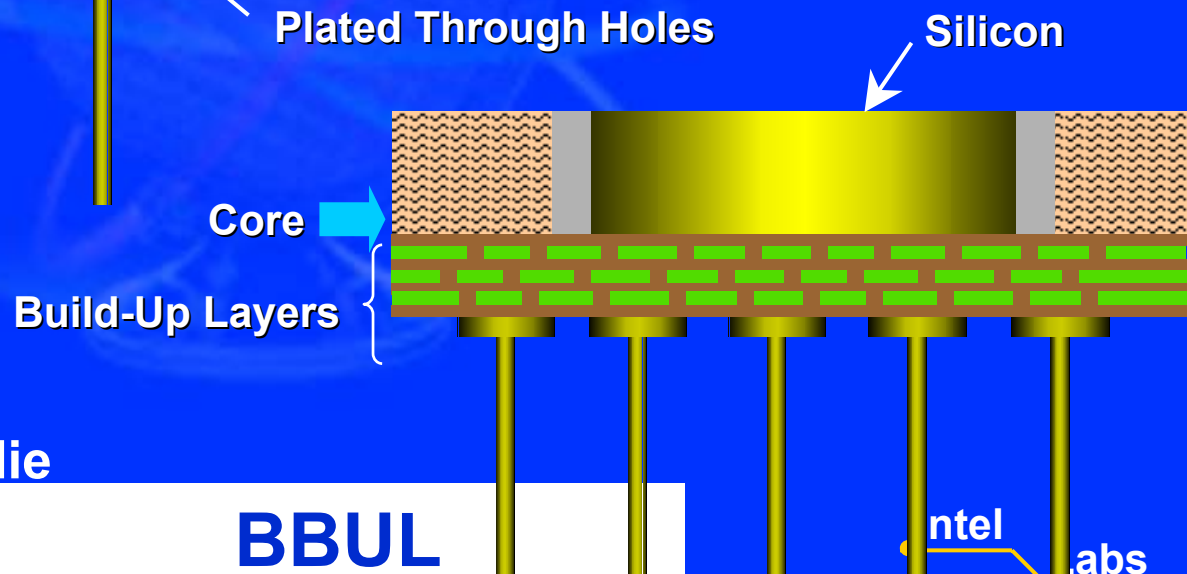
What is BBUL?

- **Bumpless Build-Up Layer**
- **A novel packaging technology**
 - Die embedded in package, not attached to its surface
 - Electrical connection between die and package made with copper lines, not C4 solder bumps
- **Key advantages:**
 - Thinner and lighter than today's packages
 - Higher performance
 - Allows incorporation of multiple silicon components in single package
 - Can help lower power

Today's Package vs. BBUL



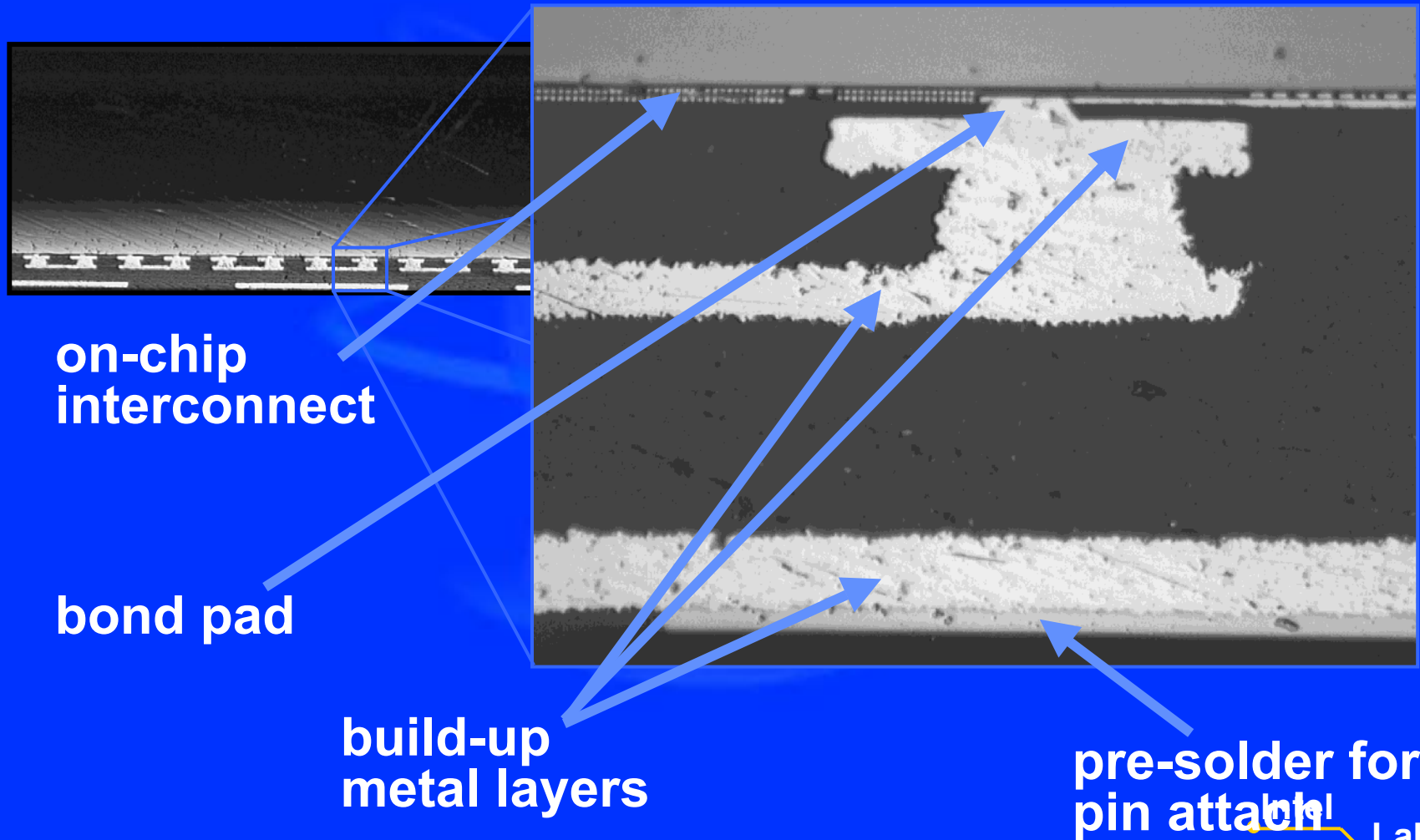
**Current
Technology**



BBUL
Die embedded in package

- No solder bumps
- Smaller pad area
- Interconnect on top of die
- Much thinner

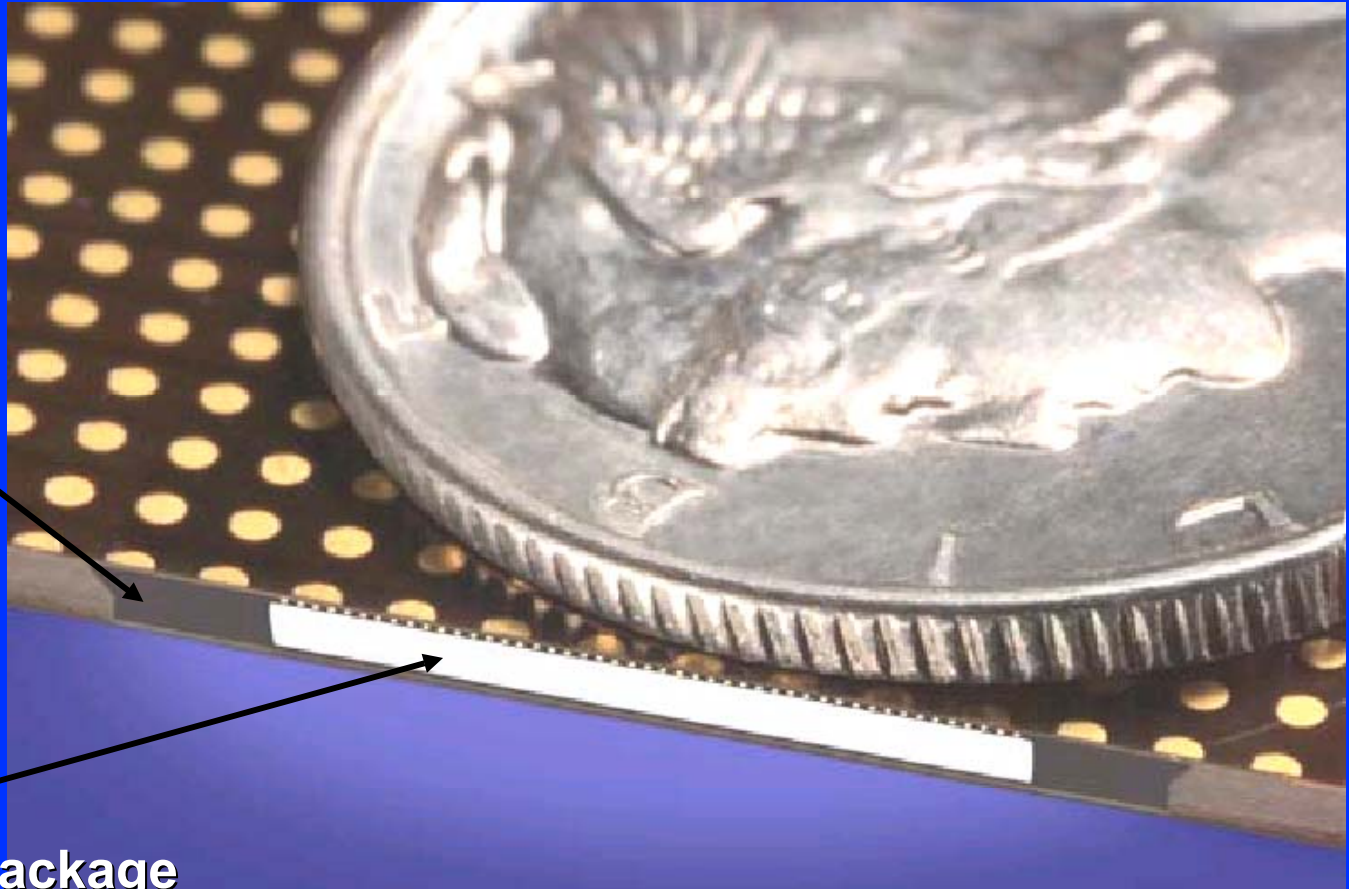
BBUL package cross section



BBUL package thinner than a dime

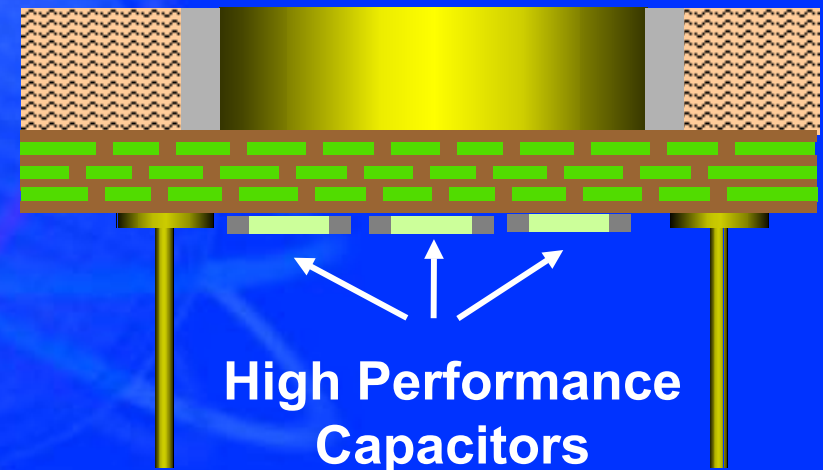
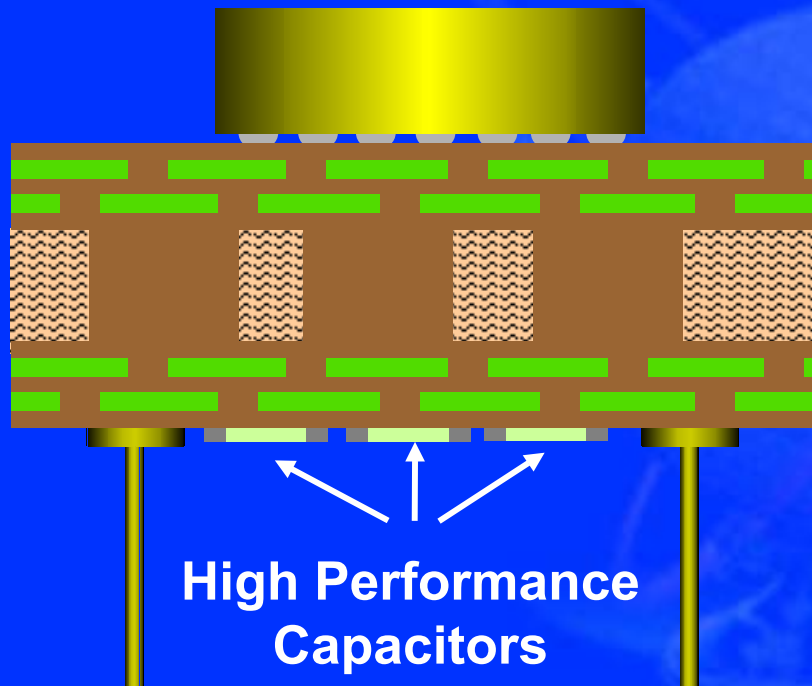
Package

Silicon die
embedded in package



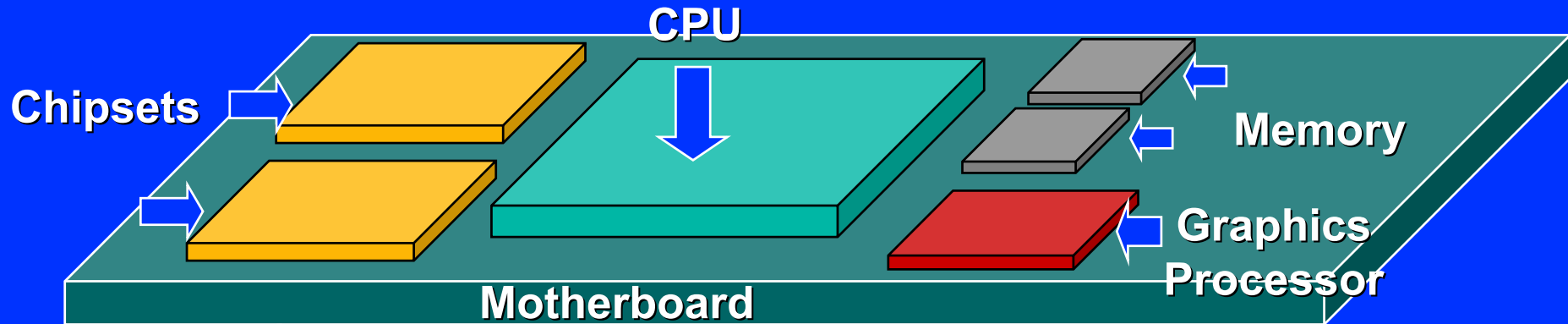
Note: This package has no pins

Capacitor Placement Allows Power Delivery Advantage

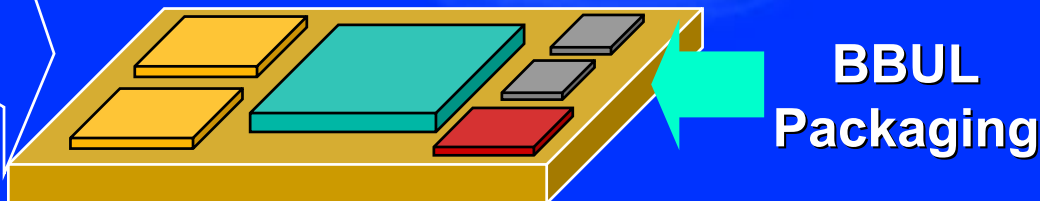


Capacitors can be placed much closer to the die – delivering power where its needed

System-on-a-Package potential



Potential to be used to create
“system-on-a-package”
designs



BBUL
Packaging

What is the significance of BBUL?

- Research demonstration of a novel embedded die package
 - High performance
 - Thinner
 - Enhanced power delivery
 - Compatible with advanced interconnects
 - Multi-chip packaging potential
- Embedded die packaging will emerge in 2nd half of this decade

Summary

- **We still have not found a fundamental barrier to Moore's Law**
 - Silicon scaling will continue through the end of this decade
 - There will be a new generation every two years
- **New materials and new structures are required**
 - Lithography
 - Transistors
 - Interconnects
 - Packaging

**For more info on Intel's
silicon technology, check out
the *Silicon Showcase* at**

www.intel.com/research/silicon